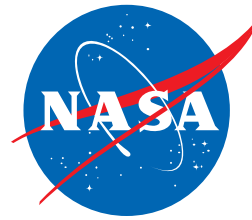


Radiation Hardness Drivers for Mission Success – What We Have Learned

Michael J. Campola,
NASA Goddard Space Flight Center (GSFC)

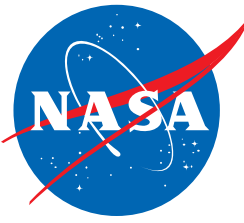
Acronyms



| | |
|----------|--|
| CME | Coronal Mass Ejection |
| COTS | Commercial Off The Shelf |
| DDD | Displacement Damage Dose |
| EEE | Electrical, Electronic, and Electromechanical |
| ELDRS | Enhanced Low Dose Rate Sensitivity |
| EP | Enhanced Performance |
| ESA | European Space Agency |
| GCR | Galactic Cosmic Ray |
| GOMAC | Government Microcircuits Applications and Critical Technologies Conference |
| GSFC | Goddard Space Flight Center |
| GSN | Goal Structuring Notation |
| HEART | Hardened Electronics and Radiation Technology |
| LEO | low earth orbit |
| LET | Linear Energy Transfer |
| MBMA | model based mission assurance |
| MRQW | Microelectronics Reliability and Qualification Workshop |
| NAND | Negated AND or NOT AND |
| NASA | National Aeronautics and Space Administration |
| NEPP | NASA Electronic Parts and Packaging |
| NEPP ETW | NASA Electronic Parts and Packaging (NEPP) Program Electronics Technology Workshop |
| NSREC | Nuclear and Space Radiation Effects Conference |

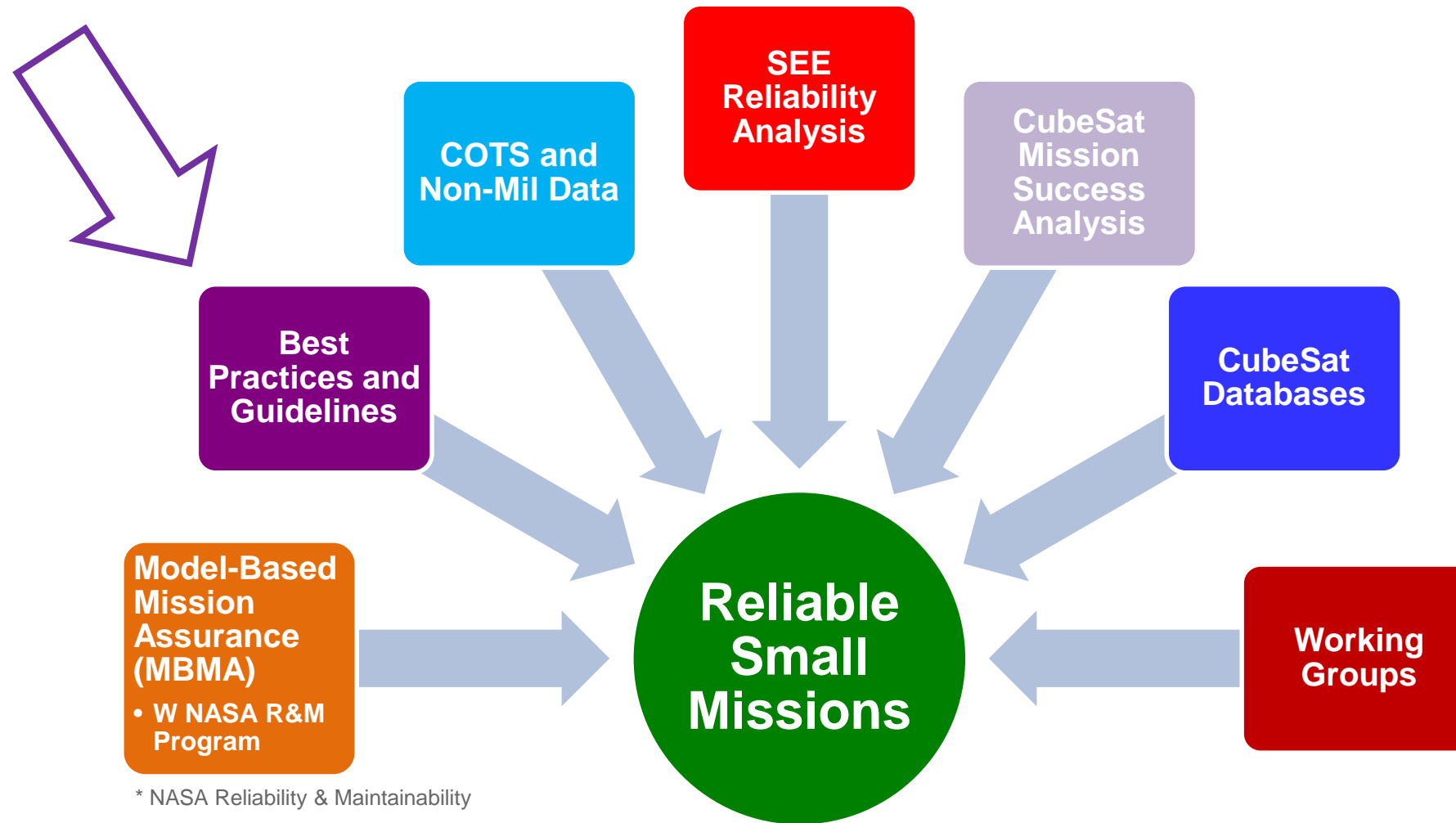
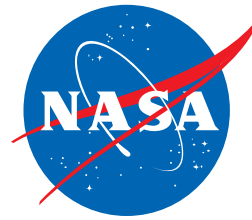
| | |
|-----------|---|
| RADECS | Radiation Effects on Components and Systems |
| RHA | Radiation Hardness Assurance |
| SAA | South Atlantic Anomaly |
| SEE | Single Event Effects |
| SEE/MAPLD | SEE-MAPLD Single Event Effects (SEE) Symposium/ Military and Aerospace Programmable Logic Devices (MAPLD) Workshop |
| SEGR | Single Event Gate Rupture |
| SEL | Single Event Latchup |
| SEP | Single Event Effects Phenomena (includes SEU, SEL, SEGR and SET) |
| SERESSA | School on the Effects of Radiation on Embedded Systems for Space Applications |
| SET | Single Event Transient |
| SEU | Single Event Upset |
| SLU | Saint Louis University |
| SwAP | Size, weight, and power |
| TID | Total Ionizing Dose |
| TID | Total Ionizing Dose |
| TMR | triple-modular redundancy |
| TNID | Total Non-Ionizing Dose |
| UV | Ultra-Violet |

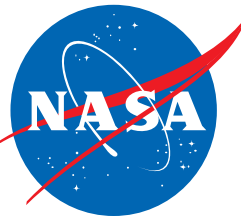
Introduction



- Embry-Riddle Aeronautical University
 - Bachelor's Engineering Physics, Space Physics Research Lab
- Arizona State University
 - Master's Electrical Engineering, Separation of Radiation and Temperature Effects, Enhanced Low Dose Rate Sensitivity
- NASA GSFC
 - Started in 2007 From Test Engineer to Radiation Lead, MMS, Juno, ICESat-2, TESS, LandSat8, DSCOVR, SMAP
 - REAG Group Lead

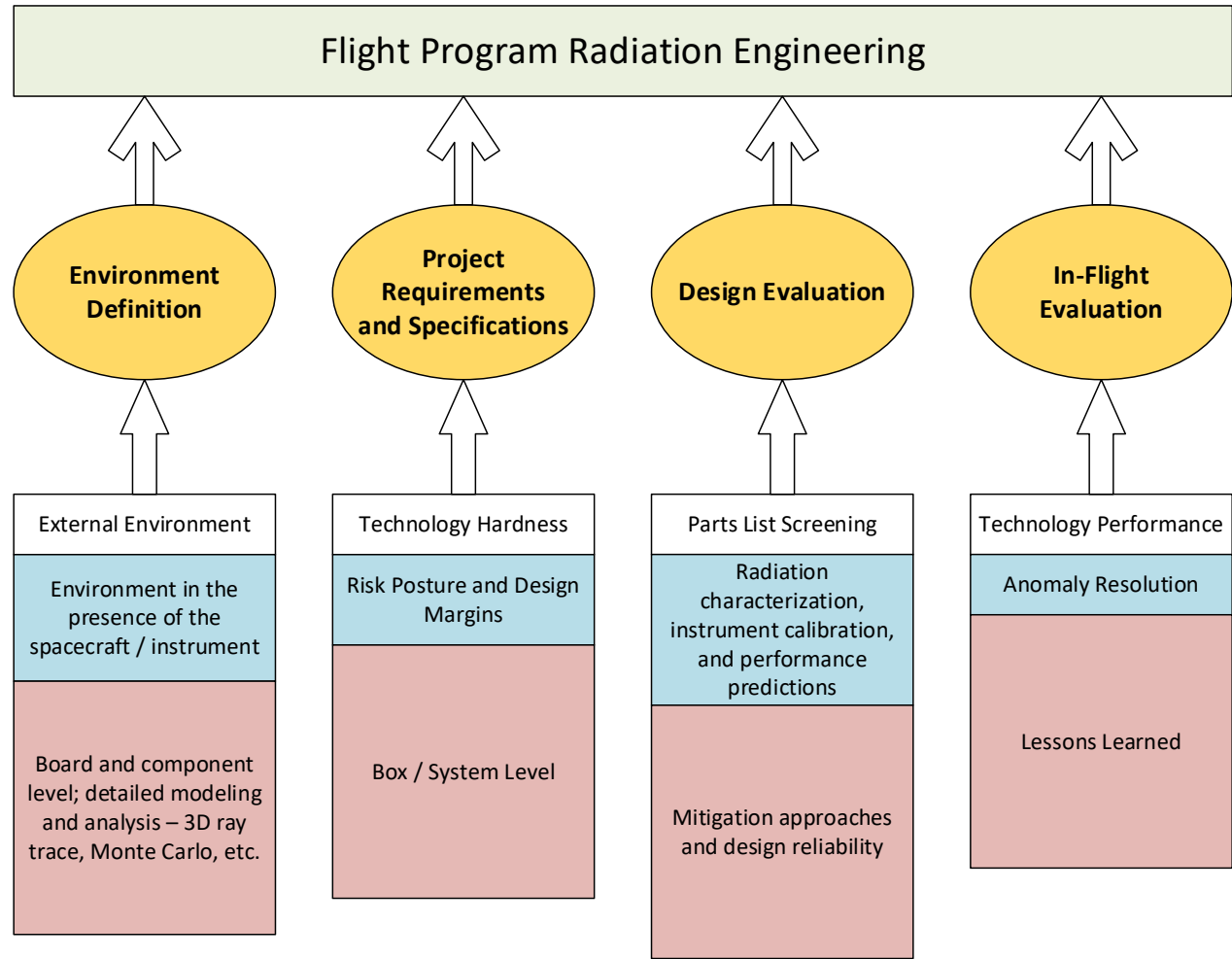
NEPP Program (OSMA)- Small Mission Efforts





Radiation Hardness Assurance (RHA) Overview

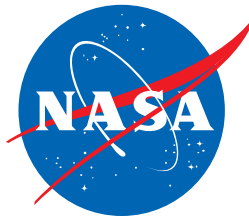
RHA consists of all activities undertaken to ensure that the electronics and materials of a space system perform to their *design* specifications throughout exposure to the mission space environment



(After Poivey 2007)

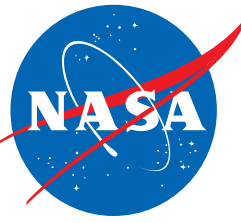
(After LaBel 2004) *Iteration over project development cycle*

Outline

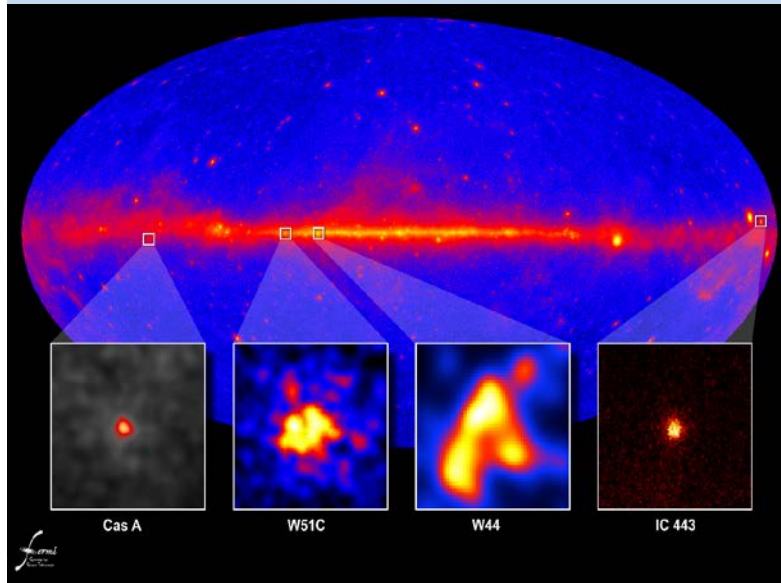


- **The Natural Space Radiation Environment Hazard**
- **Radiation Effects on Micro-Electronics**
- **New Space and SmallSat Considerations**
- **Hardness Assurance, as a Discipline, What We are Learning**
 - **New Technologies**
 - **New Architectures**
 - **Unbound Risks**
- **Risk Acceptance and Guidance**
- **RHA @ GSFC**

Natural Space Radiation Environment



Galactic Cosmic Rays



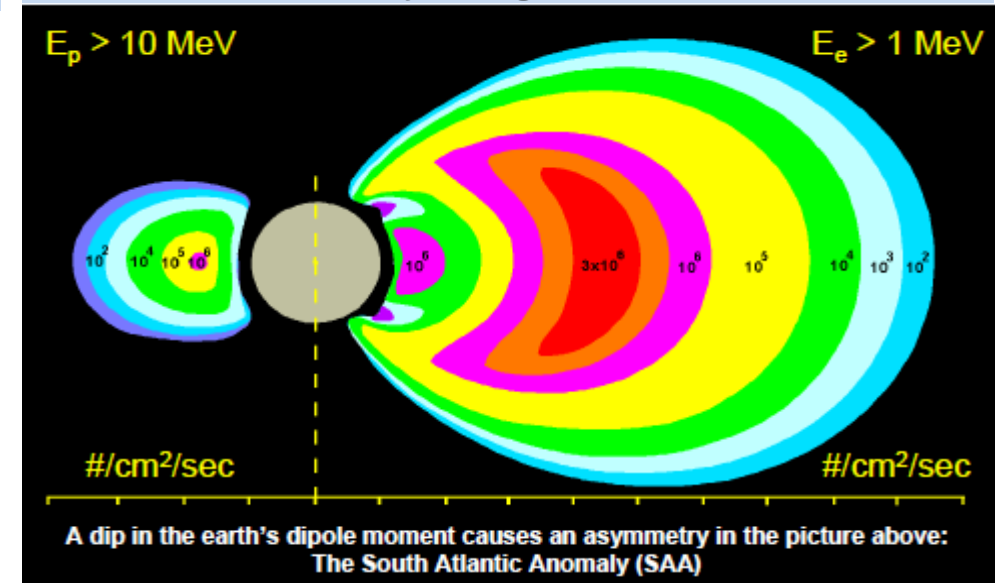
Energetic supernovae remnants
(~GeV, $Z=1-92$)
Originate outside of our solar system

Solar Activity



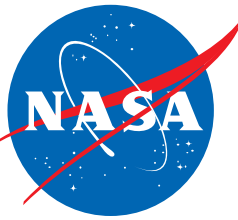
Solar Wind, Solar Cycle
CMEs (proton rich)
Flares (heavy ion rich)

Trapped Particles in Planetary Magnetic Fields



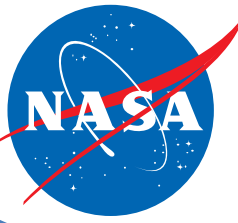
Fluctuate with Solar Activity and Events
Not a perfect dipole
Protons and Electrons trapped at different
L-shell values and energies

Summary of Environmental Hazards (Reference)



| | Plasma (charging) | Trapped Protons | Trapped Electrons | Solar Particles | Cosmic Rays | Human Presence | Long Lifetime (>10 years) | Nuclear Exposure | Repeated Launch | Extreme Temperature | Planetary Contaminates (Dust, etc) |
|---|--|--|--|-----------------|-------------|----------------|---------------------------|------------------|-----------------|---------------------|------------------------------------|
| GEO | Yes | No | Severe | Yes | Yes | No | Yes | No | No | No | No |
| LEO (low-incl) | No | Yes | Moderate | No | No | No | Not usual | No | No | No | No |
| LEO Polar | No | Yes | Moderate | Yes | Yes | No | Not usual | No | No | No | No |
| International Space Station | No | Yes | Moderate | Yes - partial | Minimal | Yes | Yes | No | Yes | No | No |
| Interplanetary | During phasing orbits; Possible Other Planet | During phasing orbits; Possible Other Planet | During phasing orbits; Possible Other Planet | Yes | Yes | No | Yes | Maybe | No | Yes | Maybe |
| Exploration – Lunar, Mars, Jupiter | Phasing orbits | During phasing orbits | During phasing orbits | Yes | Yes | Possibly | Yes | Maybe | No | Yes | Yes |

https://radhome.gsfc.nasa.gov/radhome/papers/SSPVSE05_LaBel.pdf



Natural Space Radiation Environment

- Plasma
- **Particle Radiation**
- Neutral Gas Particles
- UV and X-Ray
- Orbital Debris

wear-out

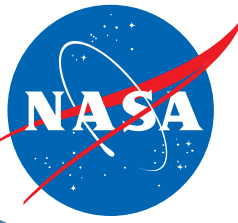
Degradation of micro-electronics
Degradation of optical components
Degradation of solar cells

instantaneous

Data corruption
Noise on images
System shutdowns or resets
Circuit Damage
Part tolerances exceeded

(After Barth)

Spacecraft Charging, Ionizing Dose, Non-Ionizing Dose, Single Event Effects, Drag, Surface Erosion, Debris/Micro-Meteoroid Impacts, Thermal Cycles



Natural Space Radiation Environment

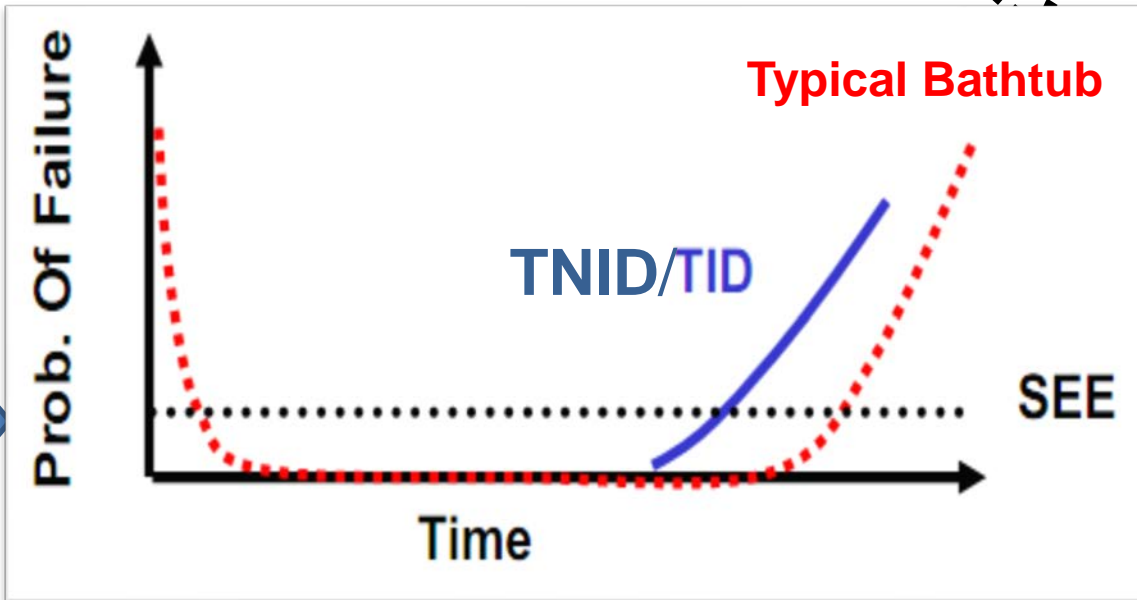
- **Particle Radiation**

wear-out

Degradation of micro-electronics
Degradation of optical components
Degradation of solar cells

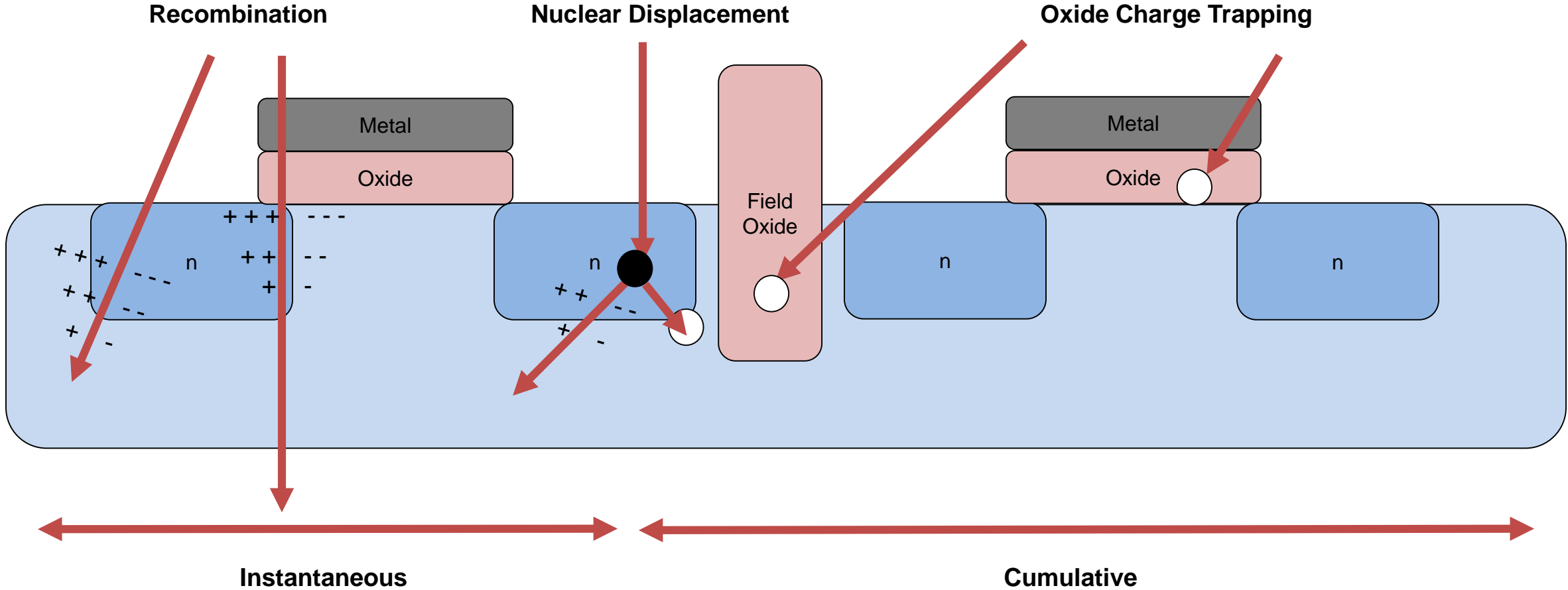
instantaneous

Data corruption
Noise on images
System shutdowns or resets
Circuit Damage
Part tolerances exceeded



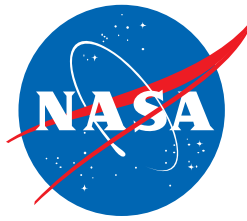
(After Buchner)

Device and Particle Interaction



Brock J. LaMeres, Colin Delaney, Matt Johnson, Connor Julien, Kevin Zack, Ben Cunningham Todd Kaiser, Larry Springer, David Klumpar, "Next on the Pad: RadSat – A Radiation Tolerant Computer System," Proceedings of the 31st Annual AIAA/USU Conference on Small Satellites, Logan UT, USA, Aug. 5-10, 2017, paper: SSC17-III-11, URL: <http://digitalcommons.usu.edu/cgi/viewcontent.cgi?article=3618&context=smallsat>

Conventional Units Explanation



Degradation

- **Total Ionizing Dose (TID)**

- Absorbed dose (rad(Si))

1 rad = 100 erg/g = 0.01 J/kg; 100 rad = 1 Gy

- Always specified for a particular material

1 rad(SiO₂), 10 krad(Si), 100 Gy(H₂O)

- This is not exposure (R), or dose equivalent (Sv)

- **Total Non-Ionizing Dose (TNID)**

- Fluence (particles/cm²)

Number of particles per unit area

- Displacement Damage Dose (DDD)

Specified at a given incident particle energy - e.g.,
10 MeV p+, 50 MeV p+, 1 MeV eq. neutrons, etc.

Single Event

- **Linear Energy Transfer (LET)**

- Stopping power normalized to target material

$$S = -\frac{dE}{dx} \Rightarrow \text{LET} = -\frac{1}{\rho} \frac{dE}{dx}$$

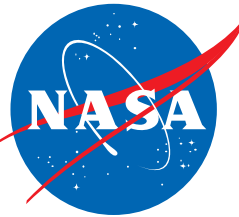
- Units are MeV·cm²/mg

- **Cross Section (σ)**

- Device particle interaction (cm²)

- Used in calculation of rate

Can be /device or /bit per time interval

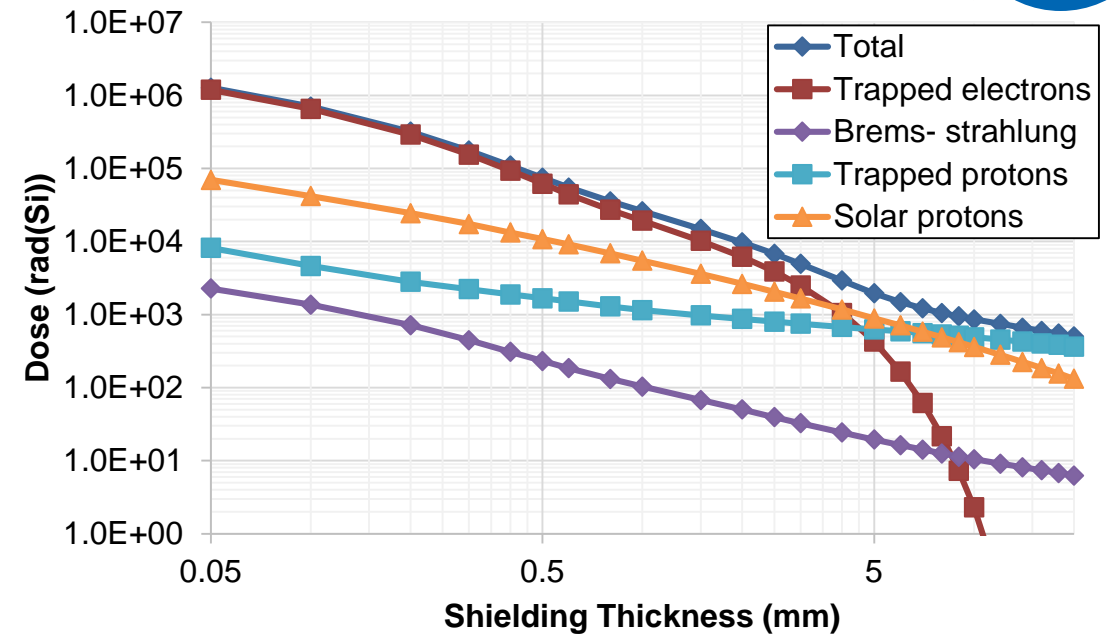


Degradation Contributors vs. Single Event

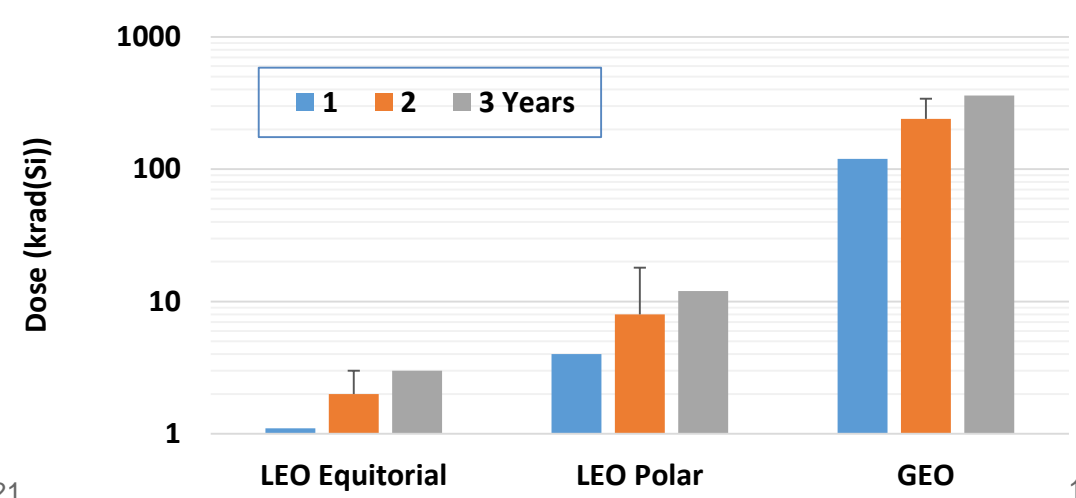
- **Cumulative effects**
 - Depend highly on which contributors and duration in their presence
 - Mimic wear-out/aging
 - TNID and TID must be accounted for
- **Typical destinations (LEO, GEO)**
 - LEO at low altitude/inclination is more protected by the Geomagnetic field
 - Proximity to the poles & SAA show a large variability in dose despite short mission durations
 - Electrons and their braking radiation are the big offender in Geostationary orbits (don't forget about spacecraft charging...)
- **Note that**
 - A little bit of shielding goes a long way
 - Altitude plays a huge role when in/near the radiation belts (even transiting)
 - Beyond Geomagnetic field, highly variable solar environment contributions (Solar cycle)

Degradation has a strong dependence on where you go, not just how long you are on orbit

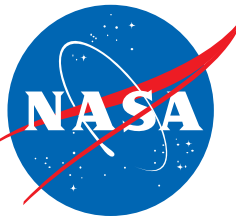
Total Ionizing Dose vs. Shielding



Approximate Dose Behind ~2.5mm Al

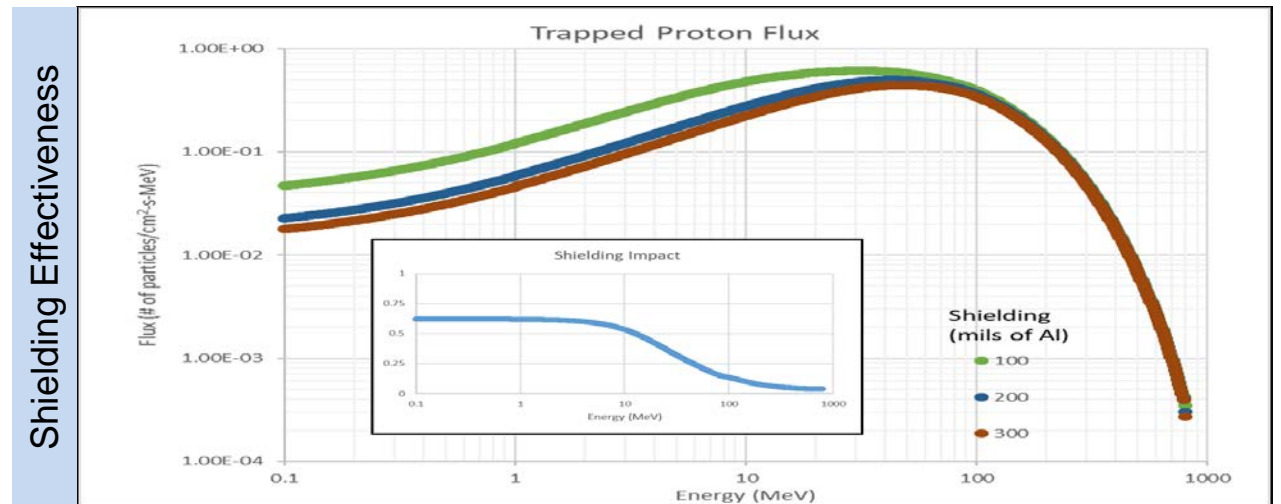
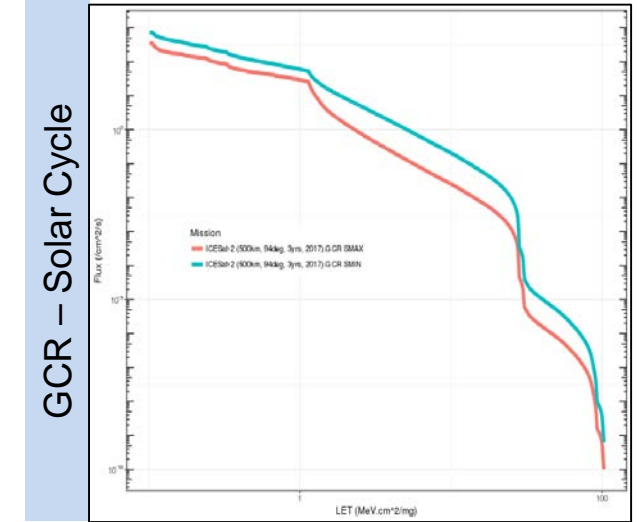
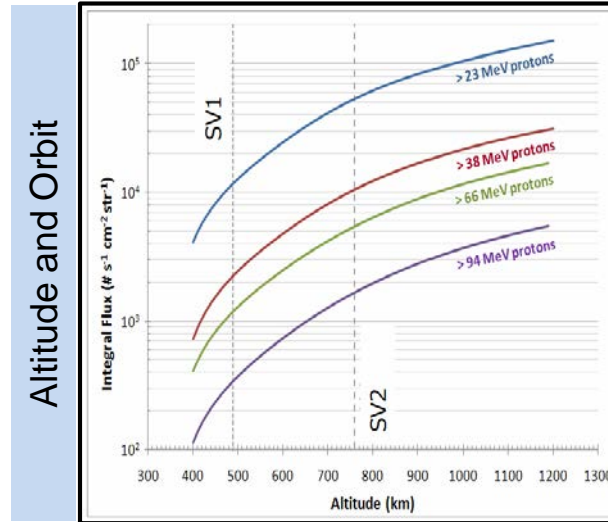


Degradation vs. Single Event Contributors

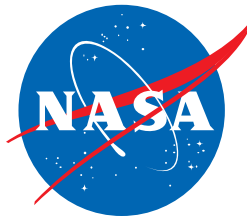


- **One particle causes the effect**
 - Random in nature, particle must traverse sensitive structure within device and have sufficient charge creation along its path
 - Shielding doesn't do so much for highly energetic particles
 - Device technology can be dependent on particle species
- **Typical Destinations (LEO, GEO)**
 - Again altitude plays a role; for some devices that is a direct threat
 - You are exposed to more GCR + Solar contribution as geomagnetic protection is reduced
 - Natural phenomena like the South Atlantic Anomaly (SAA), magnetic poles, are temporal drivers
- **Note that**
 - There will be a background rate, solar cycle dependence, solar event rate, increased rate for poles or SAA – **not just one rate to consider**

Single event contributors benefit very little from shielding, have dependence on where you are

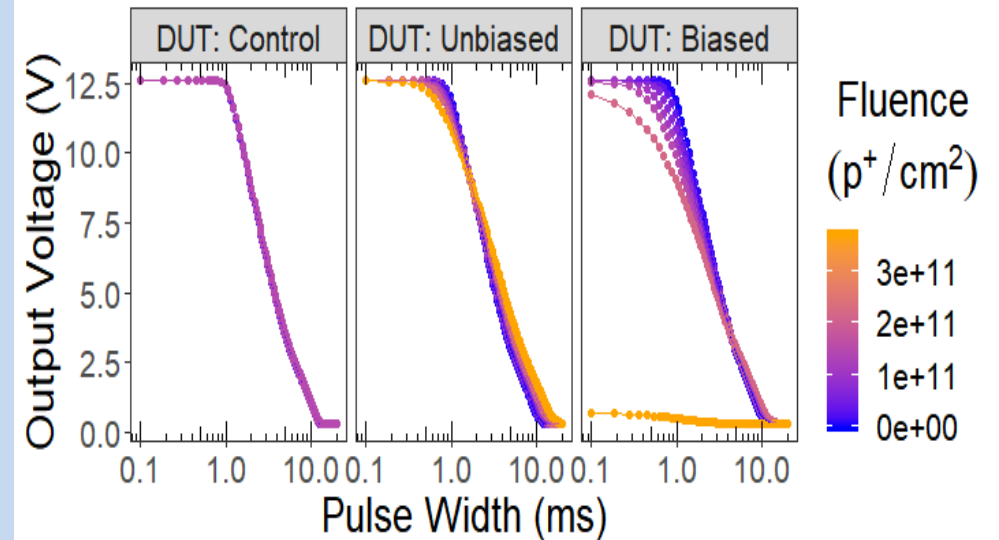


Radiation Effects on Active Microelectronic Devices

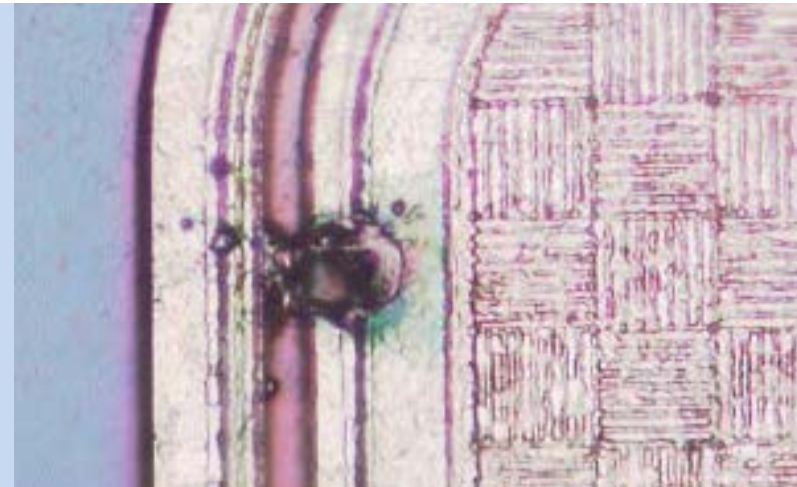


- **Cumulative effects and single event effects can both be permanently damaging**
 - TID/DDD lead to wear-out of device operation and degrade devices beyond acceptable operations internally and externally
 - Single Event Effects can be catastrophic instantaneously by turning on parasitic devices within the semiconductor or inducing electric field across dielectrics that eventually break down
 - Synergistic effects can make ground based testing very difficult
- **Destructive Single Event Effects (SEEs)**
 - Irreversible processes
 - Terms: Latchup, Burnout, Gate Rupture
- **Non-Destructive SEEs**
 - Lead to interruptions in operation and/or errors leading to unknown state spaces or loss of science / mission if not accounted for
 - Terms: Functional Interrupt, Transients, Upsets
- **IEEE / Papers / Short Courses / Presentations**
 - GOMAC, HEART, MRQW, NEPP ETW, NSREC, RADECS, SEE/MAPLD, SERESSA, SPWG

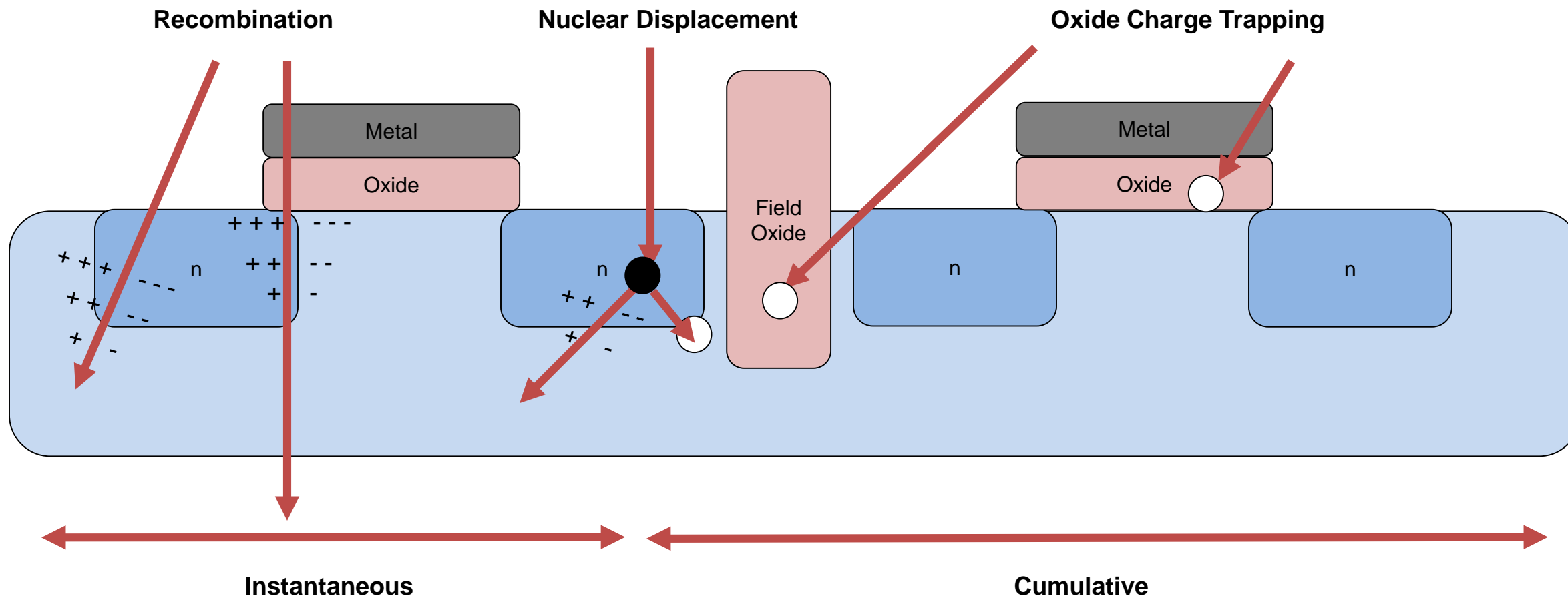
Degradation



Single Event



Device and Particle Interaction



Brock J. LaMeres, Colin Delaney, Matt Johnson, Connor Julien, Kevin Zack, Ben Cunningham Todd Kaiser, Larry Springer, David Klumpar, "Next on the Pad: RadSat – A Radiation Tolerant Computer System," Proceedings of the 31st Annual AIAA/USU Conference on Small Satellites, Logan UT, USA, Aug. 5-10, 2017, paper: SSC17-III-11, URL: <http://digitalcommons.usu.edu/cgi/viewcontent.cgi?article=3618&context=smallsat>



Table of SEE Susceptibility

| SEL | SEGR | SEB | SEDR | Stuck Bit | SEU/MCU | SET | SEFI |
|----------|----------------|--------------|-----------------------|-----------|--|----------------------|-----------------------|
| CMOS | MOSFET | POWER MOSFET | One-time Prog. FPGA | SRAM | Digital/bistable technologies | bipolar technology | Complex Microcircuits |
| Bipolar? | FLASH | Power JFET | Bipolar Microcircuits | DRAM | Deep submicron CMOS more MCU susceptible | Analog microcircuit | ADCs |
| | Schottky Diode | Power BJT | | FLASH | | Digital microcircuit | PWMs |

Part-Level Consequences

- Catastrophic failure possible
- Destructive but limited
- Nondestructive

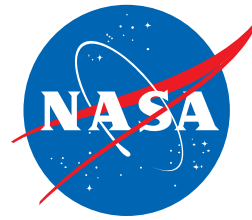
How Common is Issue?

- Common in technology
- Catastrophic failure possible
- Not seen but possible in principle

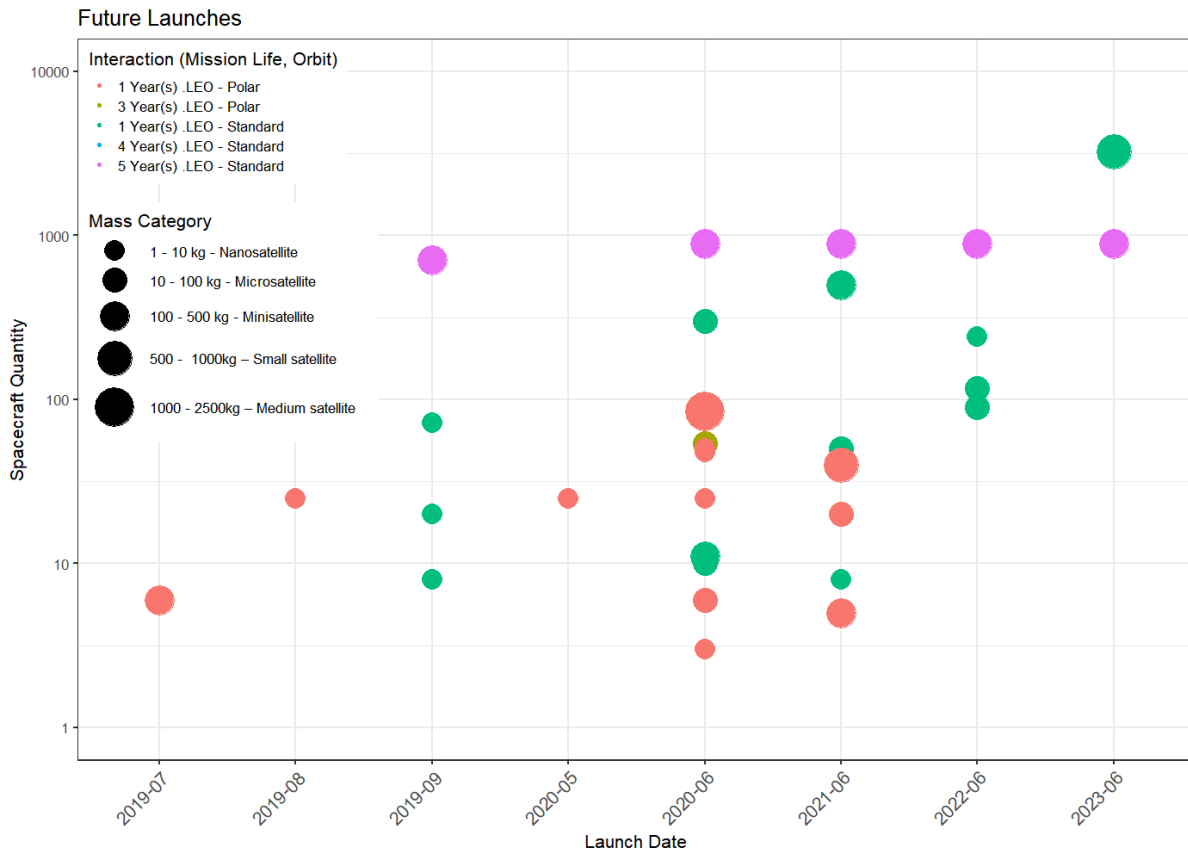
Ray Ladbury, <https://ntrs.nasa.gov/archive/nasa/casi.ntrs.nasa.gov/20170006865.pdf>

List is not exhaustive, but new failure modes are found in new devices, so it would not be possible to capture all

New Space – Looking Ahead

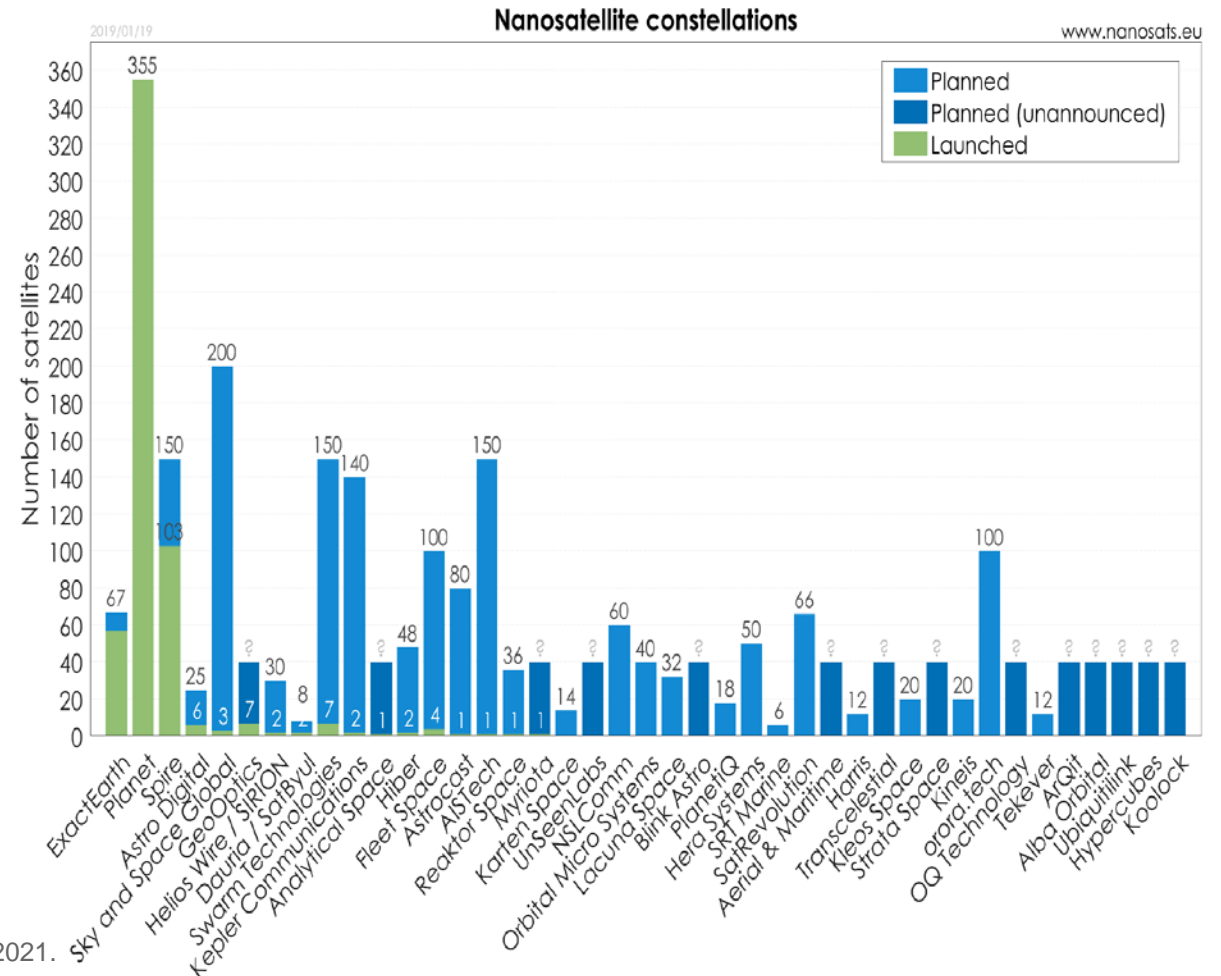


Constellations and Swarms



Seradata SpaceTrak Data (Notional Launches)

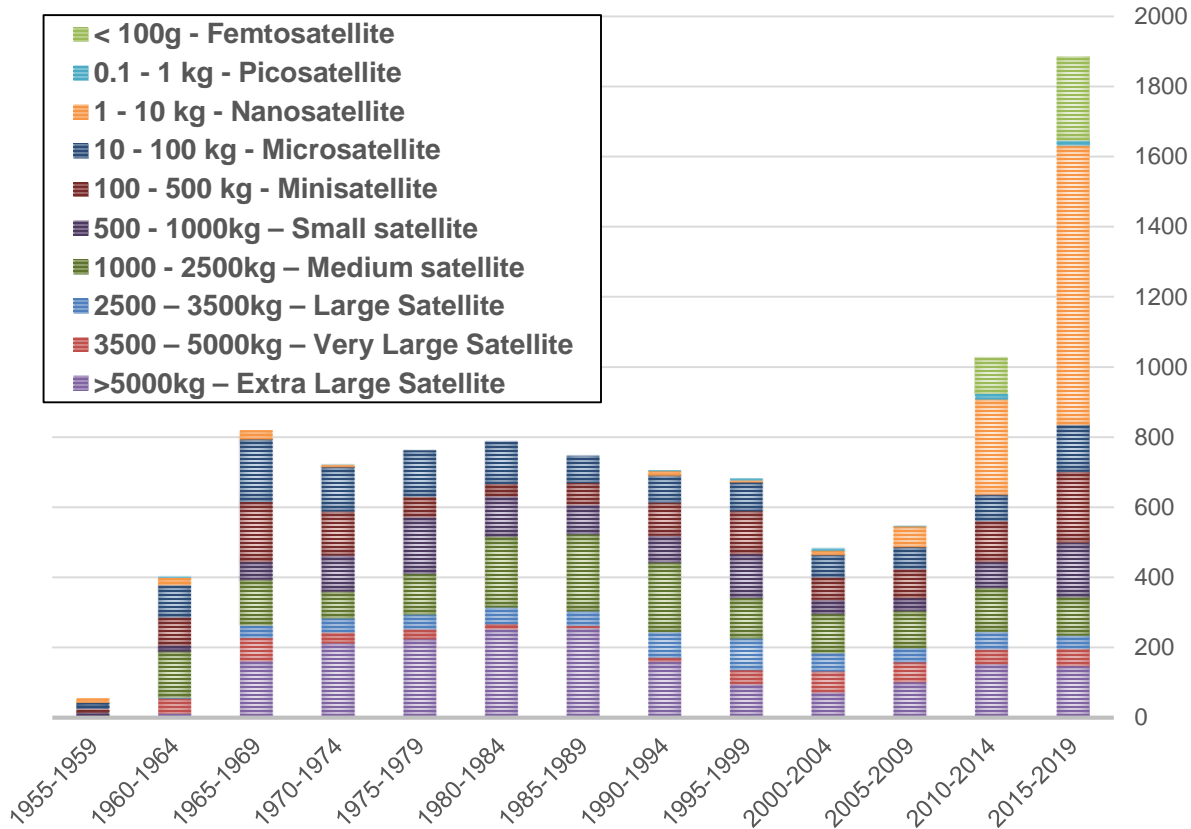
New Space = New Companies



New Space – New Point of View

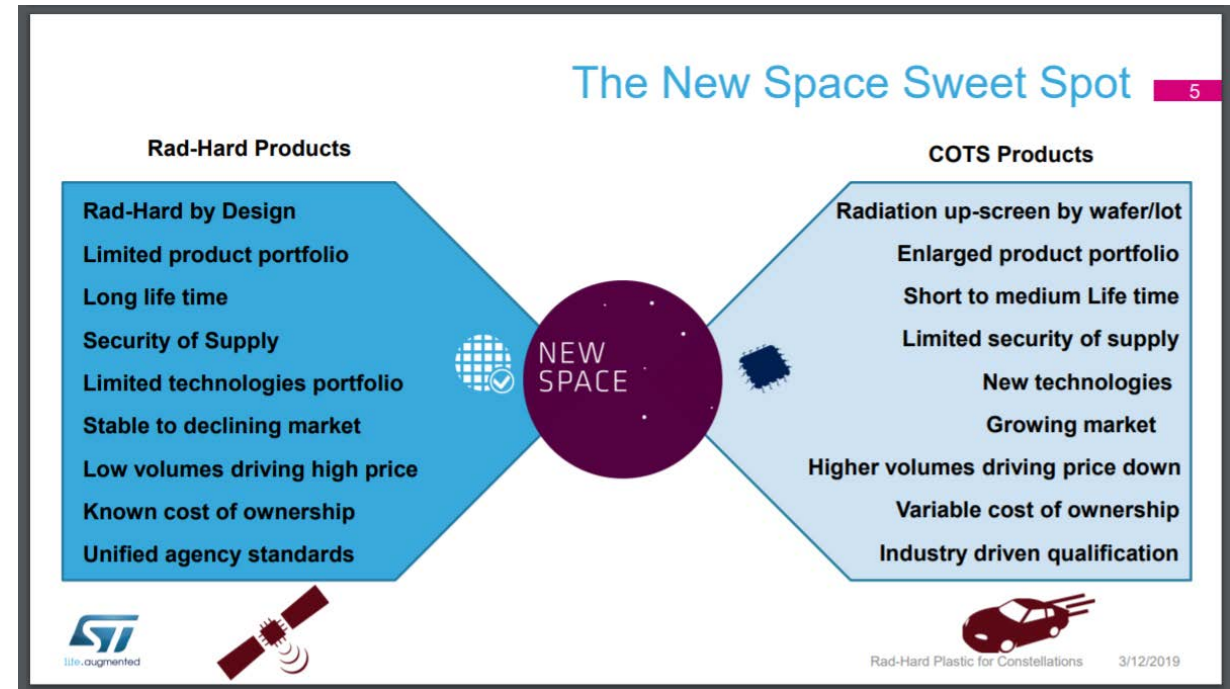


SmallSats Come in Many Sizes



Seradata SpaceTrak Data

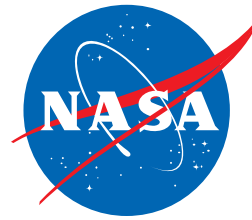
Component Grades are Merging



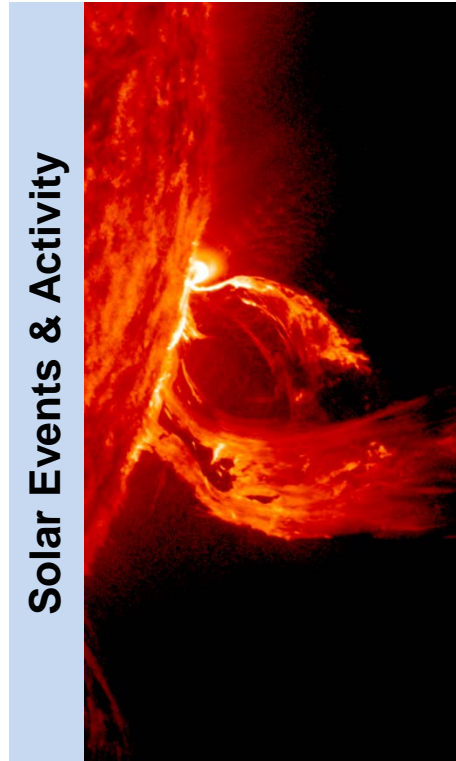
ESSCON : Eccofet

Risk acceptance is being used as a means to enable innovation

New Space – Same Old Radiation

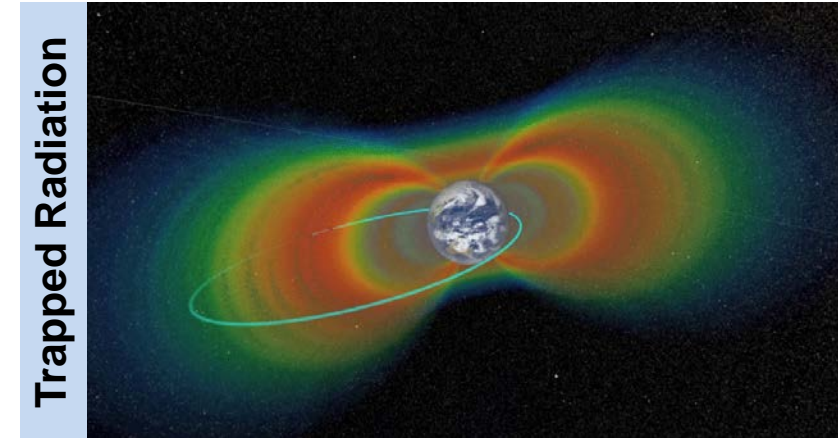


- **New mission concepts and SmallSat paradigm**
 - Radiation challenges identified in the past are here to stay; adoption of new technologies are often the risk driver
 - Commercial Space, Constellations, Small missions, etc. will benefit from detailed hazard definition and mission specific requirements
- **The need for Radiation Hardness Assurance (RHA)**
 - Radiation effects are a mix of disciplines, evolve with technologies and techniques
 - Misinterpretation of failure modes / misuse of available data can lead to over/under design
 - RHA flow doesn't change, risk acceptance needs to be tailored
- **Some Top Level Resources**
 - NPR-7120.5 – NASA Agency Program Management
 - GPR-8705.4 – NASA Goddard Risk Classification Guidelines
 - NASA-STD-8739.10 – NASA Parts Assurance Standard



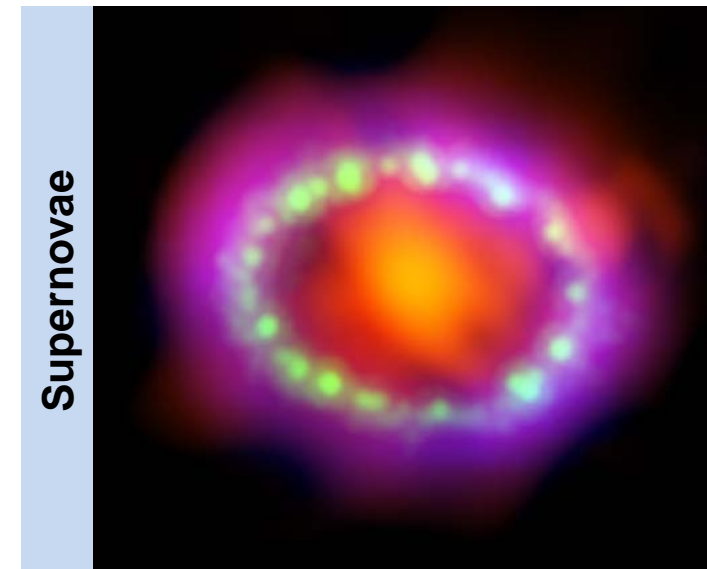
Solar Events & Activity

<https://sdo.gsfc.nasa.gov>



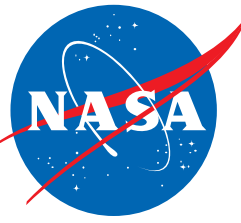
Trapped Radiation

<https://www.nasa.gov/van-allen-probes>



Supernovae

[NASA, ESA, and L. Hustak \(STScI\)](#) 21



Who Needs This Guidance?

- **Universities / CubeSats**

- May be first-time designers, or previous missions did not have requirements
- Schedule driven, limited time for development
- Rideshares – could end up in multiple environments

- **Space Agencies / Government**

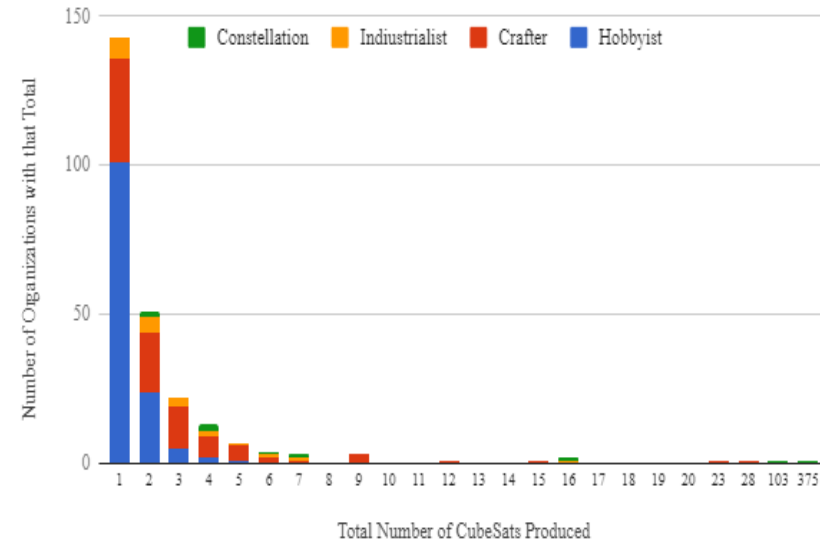
- More compact designs in new destinations
- Cost savings of SmallSat platform, with more reliable outcome
- More willing to trade risk for capability

- **Device / Subsystem Manufacturers**

- Product / Device offerings: Space Plastic, EP, LeanRel, radiation tolerant, modified HiRel, etc.
- Fault tolerance in designs

CubeSat Metrics

Total Count of CubeSats Produced by an Organization



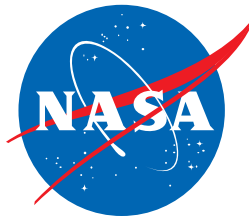
Michael Swartwout, SLU CubeSat Database

Dellinger

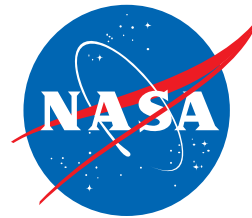


NASA's Goddard Space Flight Center/Bill Hrybyk

Outline



- The Natural Space Radiation Environment Hazard
- Radiation Effects on Micro-Electronics
- New Space and SmallSat Considerations
- **Hardness Assurance, as a Discipline, with its Challenges**
 - **New Technologies**
 - **New Architectures**
 - **Unbound Risks**
- **Risk Acceptance and Guidance**
- **RHA @ GSFC**



The Job: Watch For the 'ilities

Survivability

- Must survive until needed
- Entire mission?
- Screening for early failures in components

Availability

- Must perform when necessary
- Subset of time on orbit
- Operational modes
- Environmental response

Criticality

- Impact to the system
- Part or subsystem function
- Mission objectives

Reliability

- Resultant of all
- Many aspects and disciplines
- Known unknowns

The People: Radiation Effects Engineers

Materials

- Material Property degradations with radiation
- Energy loss in materials

Device Physics

- Charge transport
- Device Process Dependencies
- Charge dependency of device operation

Electrical Engineering

- Part to part interconnections
- Understanding circuit response
- Device functions and taxonomy

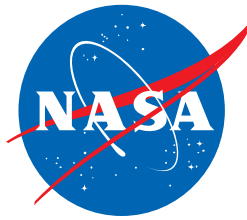
Systems Engineering

- Requirements
- System Level Impacts
- Understanding interconnections
- Understanding functionality

Space Physics

- Space weather
- Environment models/modeling
- Radiation Sources and variability

Paths to Space Radiation



Space Radiation Ecosystem

Systems
Engineering
Background

- Radiation Reqs. Definition
- SPENVIS, OMERE, Fastrad, etc.
- Radiation Testing Management

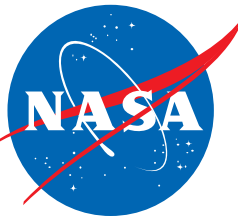
Device Physics /
Electrical Engineering
Background

- Radiation Testing + Qualification
- EEE Parts Programs

Space Weather
Physics
Background

- Mission Scientists / PIs
- Model Developers (e.g. AP9/AE9)
- Often University + Research Lab based

After Whitney Lohmeyer, presented at JPL meeting 2019



RHA Challenges... Not So Small

- Always in a **dynamic** environment
- **New Technologies**
 - Device Topology / Speed / Power
 - Increased COTS parts / subsystem usage
- **New Mission Architectures**
 - Profiles of mission life, objective, and cost are evolving
 - Oversight gives way to insight in some mission classifications
 - Ground systems, do no harm, hosted payloads
 - Similarity and heritage data requirements widening
- **Quantifying Risk**
 - Translation of system requirements to radiation trades can be problematic
 - Determining appropriate mitigation level (operational, system, circuit/software, device, material, etc.)

Unbound radiation risks are likely

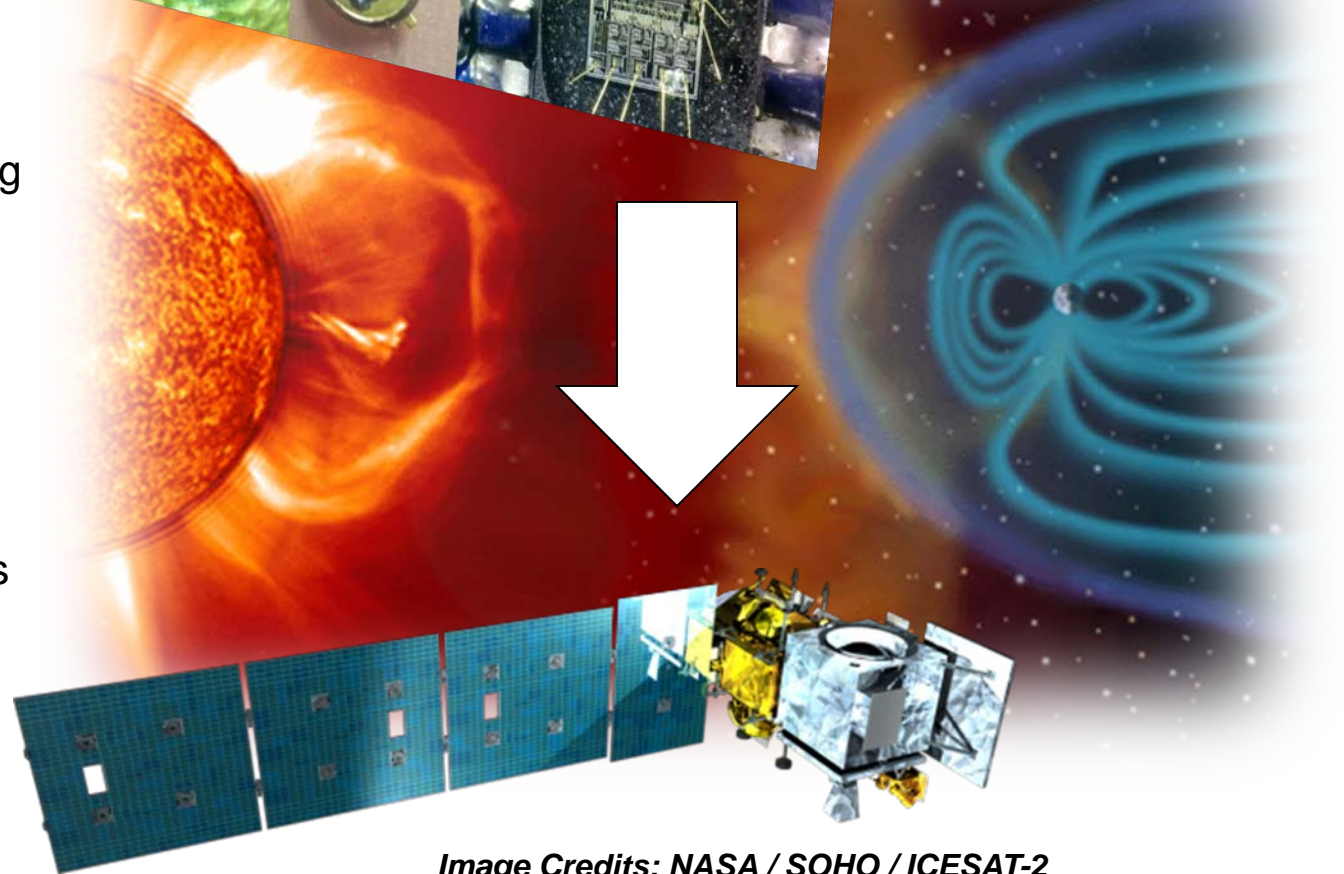
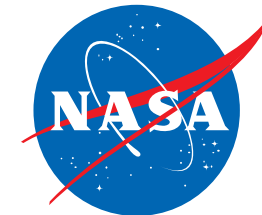


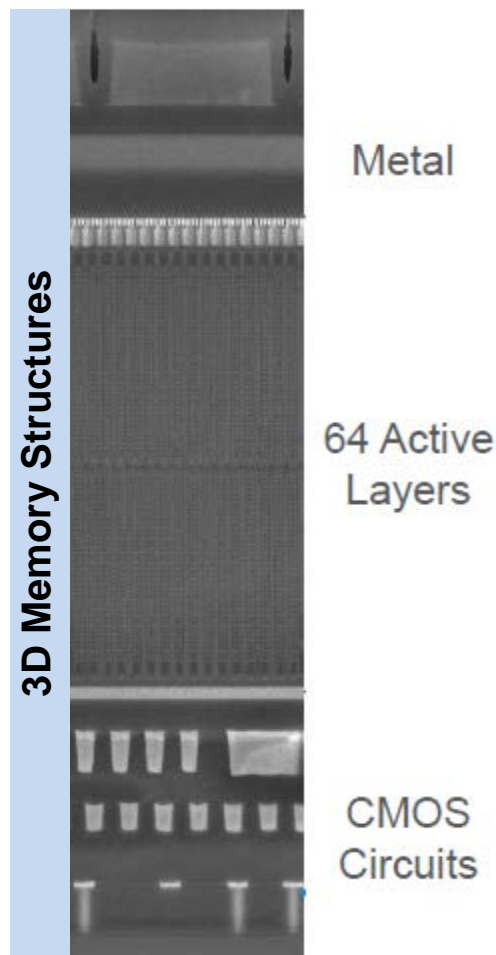
Image Credits: NASA / SOHO / ICESAT-2

New Technologies - New Susceptibilities

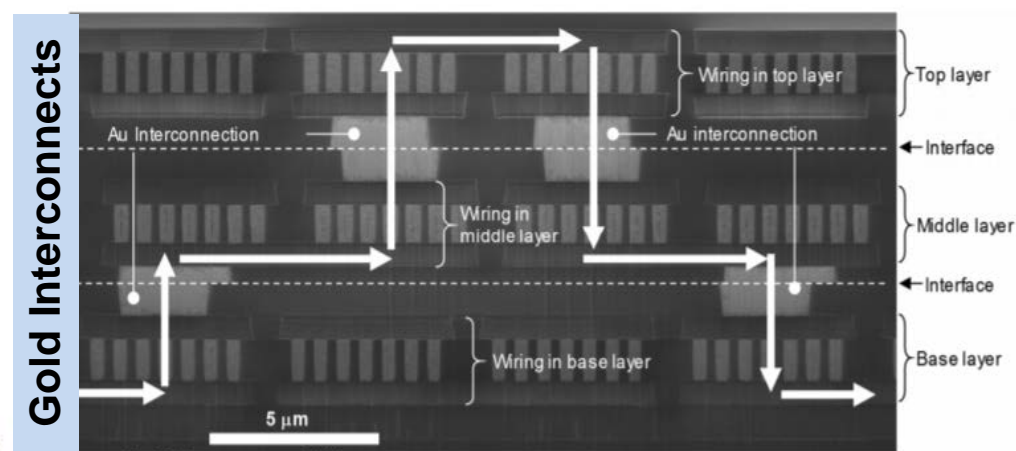


- **Feature Size / Critical Charge**
 - Sensitivity to muons? Low energy protons?
- **3D Stacking / Structures**
 - Deep sensitive volumes
 - New materials within structure
- **Testing Challenges**
 - Complexity (e.g., Systems-on-a-Chip)
 - Speed of interfaces
 - Obfuscation of state-space
 - Flux / range of beam at facilities
- **Function**
 - Integrated Photonics, MEMS, Hybrids

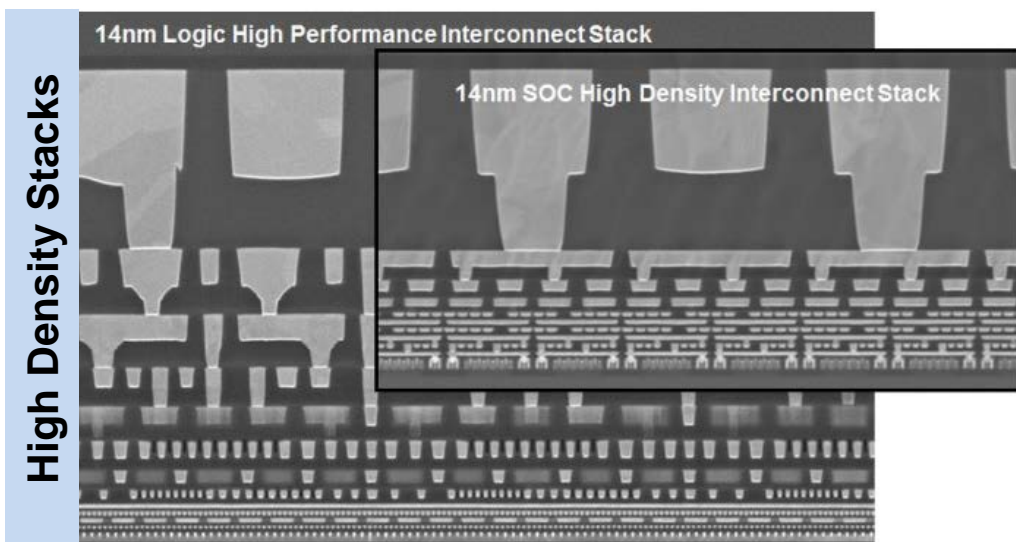
Without detailed part information you do not have certainty of the radiation threats



www.micron.com



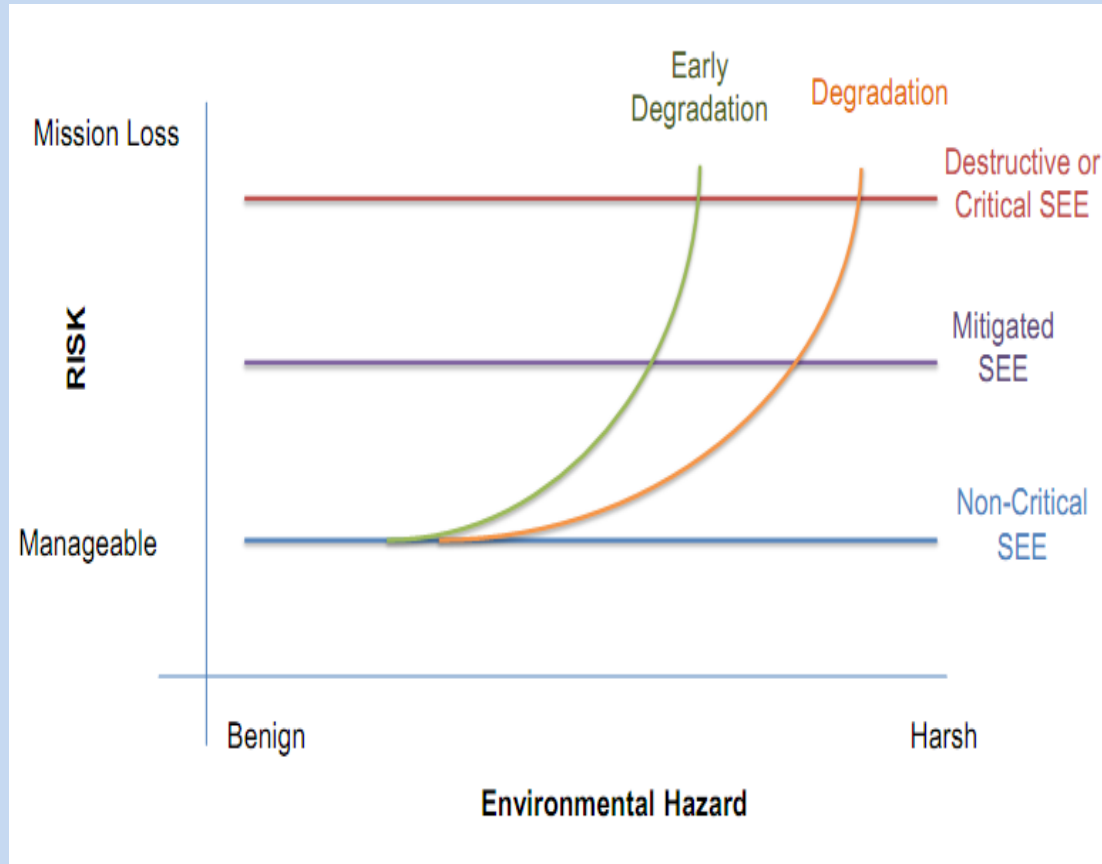
IEEE/DOI: [10.1109/TCPMT.2019.2910863](https://doi.org/10.1109/TCPMT.2019.2910863)



New Mission Architectures - How Many to Succeed?

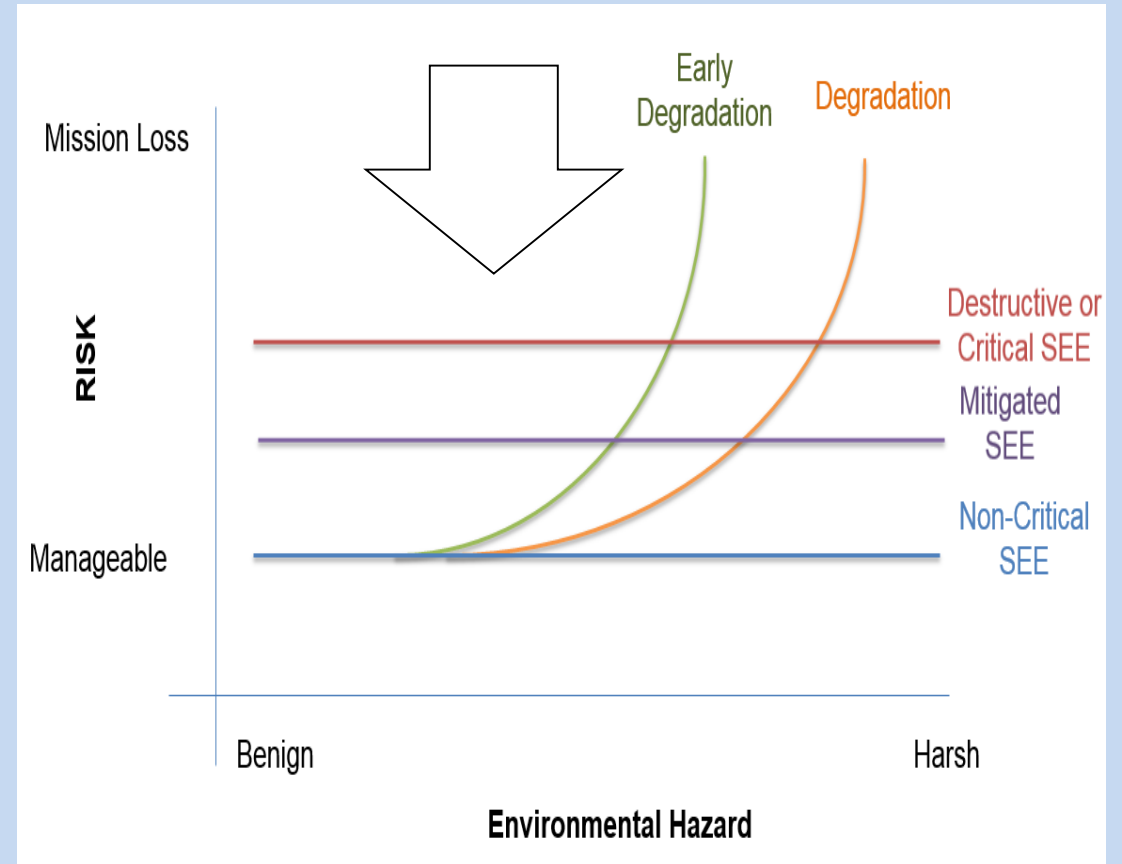


Single String

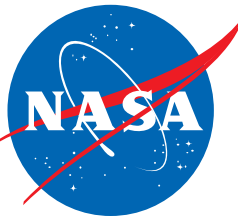


VS

Allowable Losses



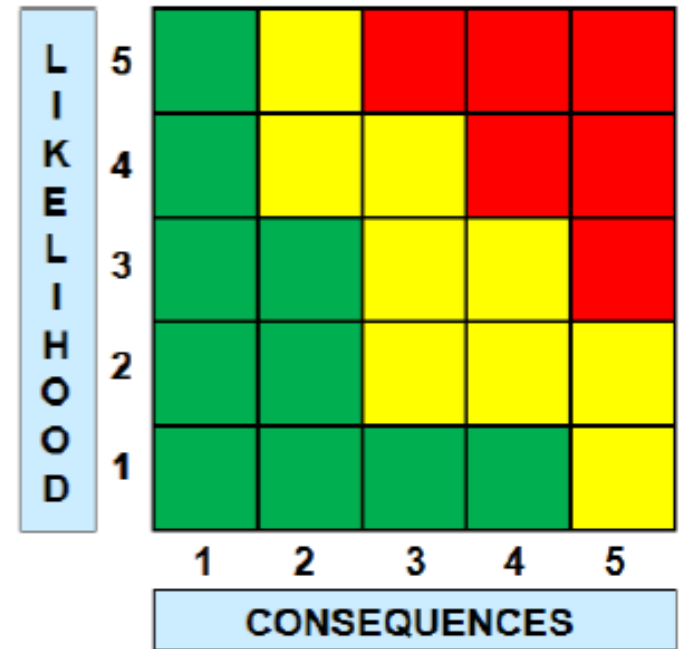
Redundancy alone does not remove the threat, adds complexity



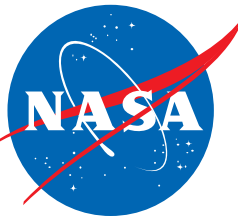
New Challenges in Quantifying Risk

From Risk Assessment section of NASA Program Management 7120.5

| Likelihood | Safety Estimated likelihood of Safety event occurrence | Technical Estimated likelihood of not meeting performance requirements | Cost Schedule Estimated likelihood of not meeting cost or schedule commitment |
|-------------|---|---|--|
| 5 Very High | $(P_{SE} > 10^{-1})$ | $(P_T > 50\%)$ | $(P_{CS} > 75\%)$ |
| 4 High | $(10^{-2} < P_{SE} \leq 10^{-1})$ | $(25\% < P_T \leq 50\%)$ | $(50\% < P_{CS} \leq 75\%)$ |
| 3 Moderate | $(10^{-3} < P_{SE} \leq 10^{-2})$ | $(15\% < P_T \leq 25\%)$ | $(25\% < P_{CS} \leq 50\%)$ |
| 2 Low | $(10^{-5} < P_{SE} \leq 10^{-3})$ | $(2\% < P_T \leq 15\%)$ | $(10\% < P_{CS} \leq 25\%)$ |
| 1 Very Low | $(10^{-6} < P_{SE} \leq 10^{-5})$ | $(0.1\% < P_T \leq 2\%)$ | $(2\% < P_{CS} \leq 10\%)$ |



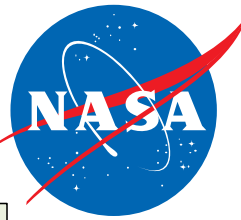
Can only get there with enough information about the system or the chosen device, need to have a known hazard and a known response



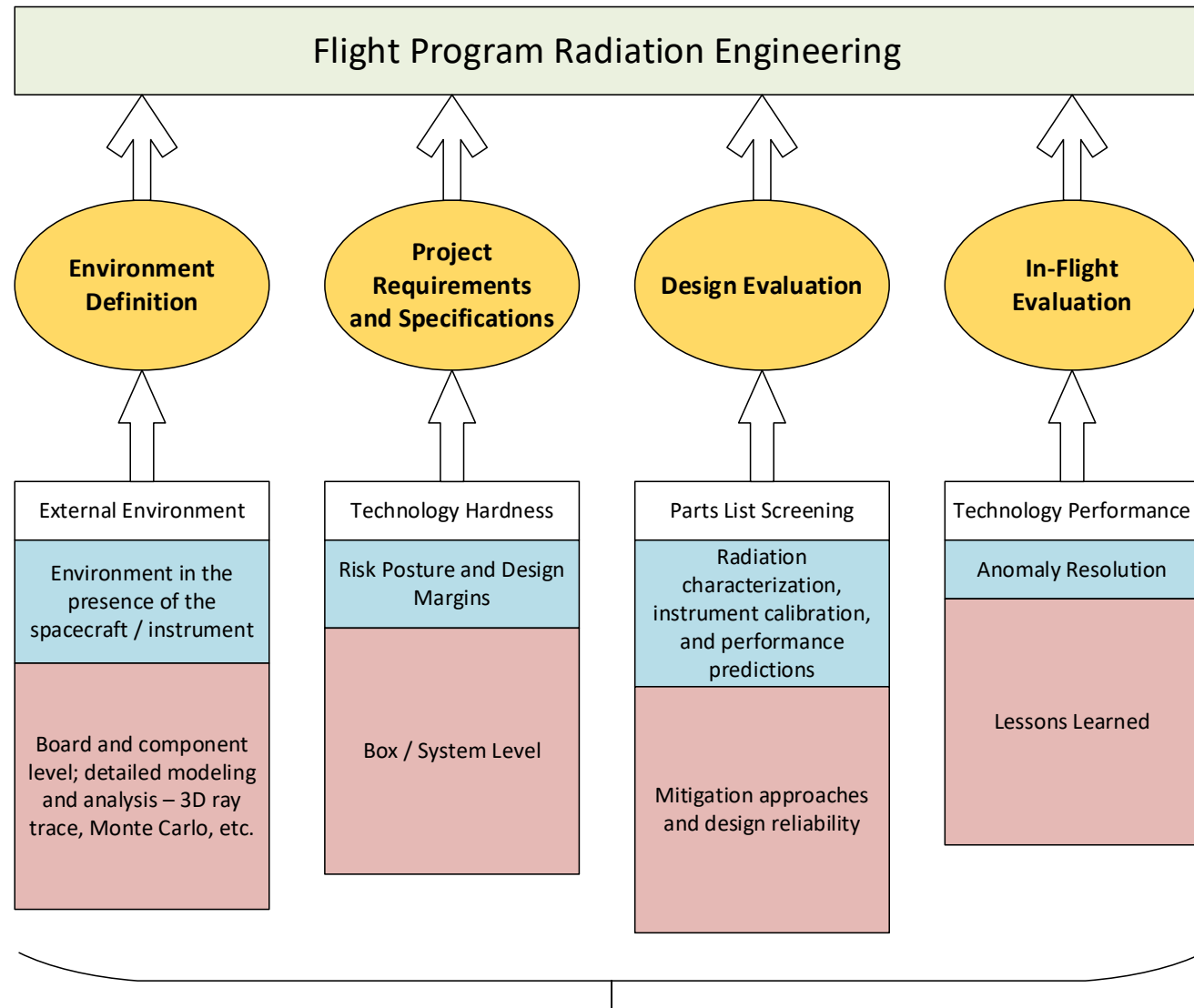
That Seems Difficult, Now What?

- We know we have challenges, but:
 - New technologies enable progress
 - New architectures enable solutions to problems with past missions
 - Quantifying the risk helps communicate across disciplines
- What can we do if we know there are going to be clear and present risks?
- How can we verify that our requirements have been met?

Radiation Hardness Assurance (RHA) Overview

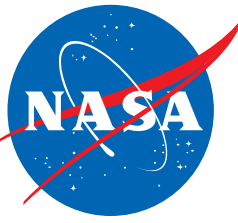


RHA consists of all activities undertaken to ensure that the electronics and materials of a space system perform to their *design* specifications throughout exposure to the mission space environment



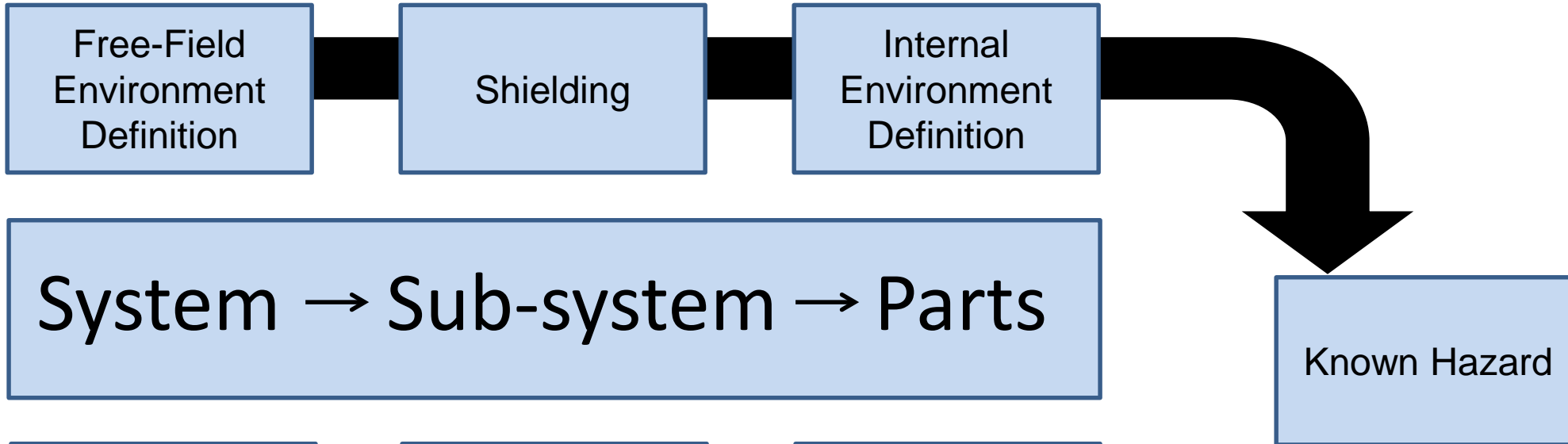
(After Poivey 2007)

(After LaBel 2004) Iteration over project development cycle

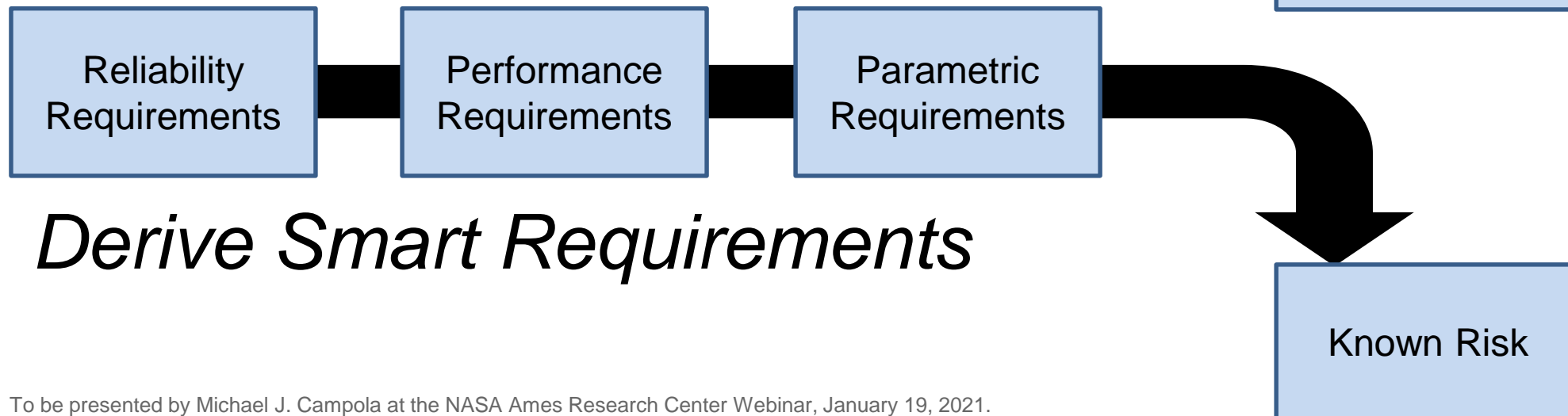


RHA Building Blocks

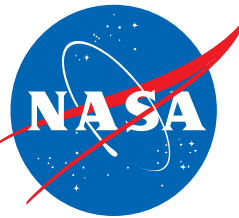
Define and Evaluate the Hazard



Derive Smart Requirements

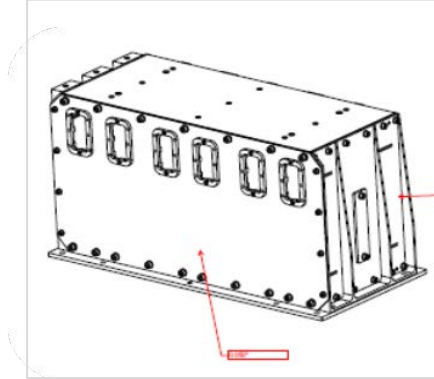
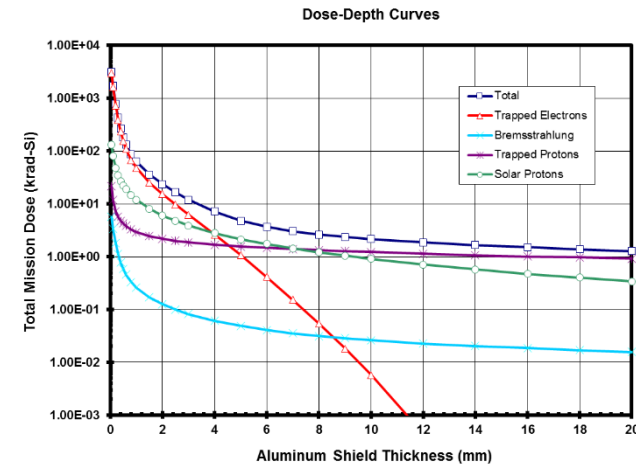


RHA Step-by-Step

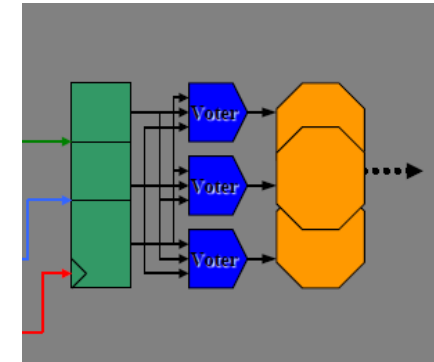
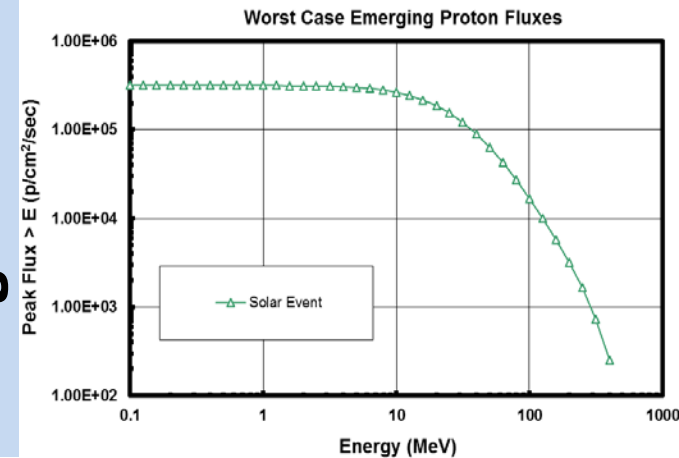


- **Define the Environment**
 - External to the spacecraft
- **Evaluate the Environment**
 - Internal to the spacecraft
- **Define the Requirements**
 - Define criticality factors
- **Evaluate Design/Components**
 - Existing data/Testing
 - Performance characteristics
- **“Engineer” with Designers**
 - Parts replacement/Mitigation schemes
- **Iterate Process**
 - Review parts list based on updated knowledge

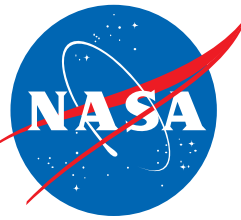
Degradation



Single Event

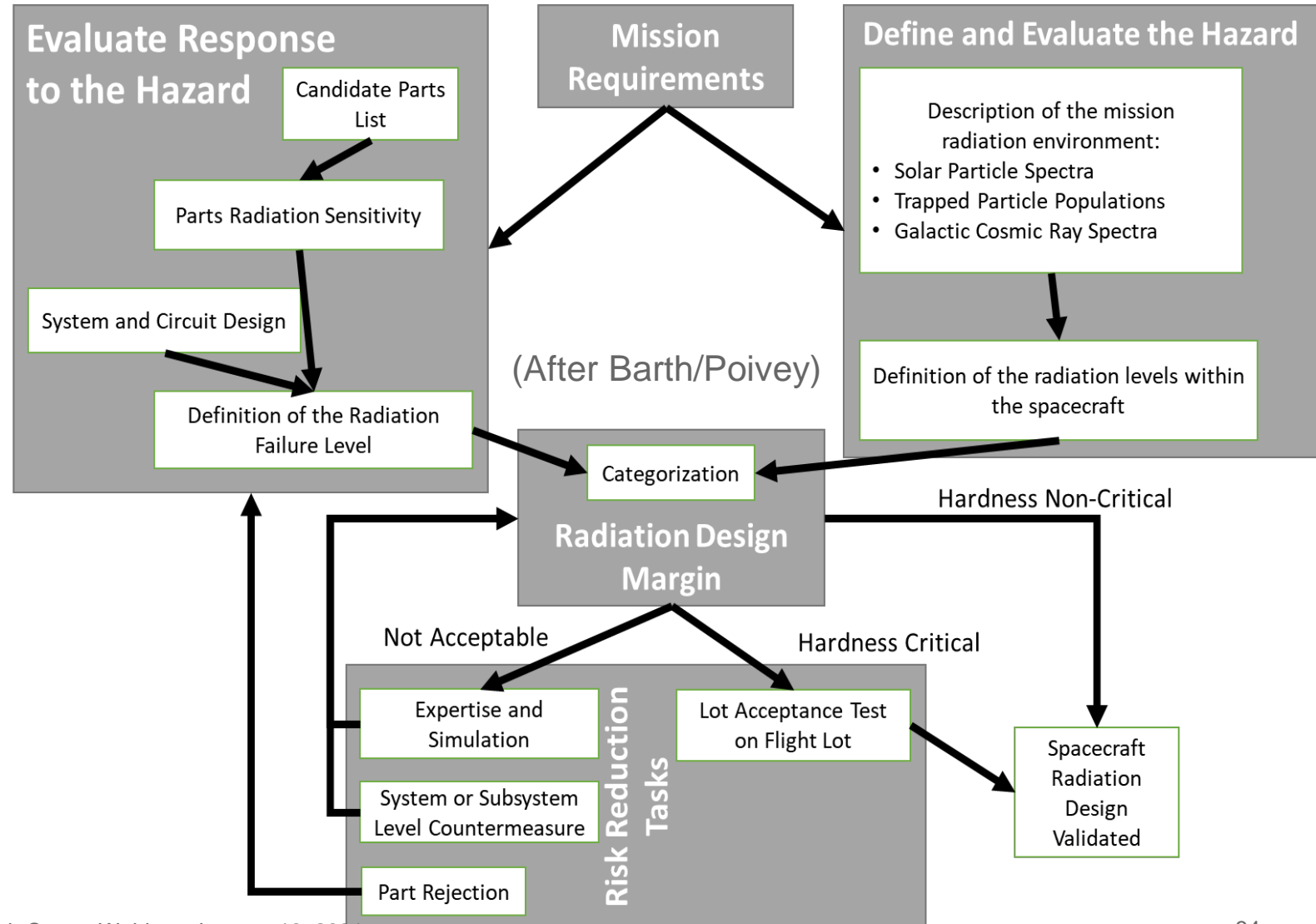


K.A. LaBel, A.H. Johnston, J.L. Barth, R.A. Reed, C.E. Barnes, “Emerging Radiation Hardness Assurance (RHA) issues: A NASA approach for space flight programs,” *IEEE Trans. Nucl. Sci.*, pp. 2727-2736, Dec. 1998.

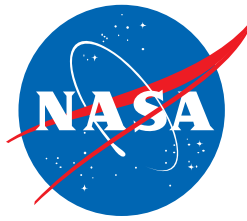


RHA Flow Doesn't Change With Accepted Risk

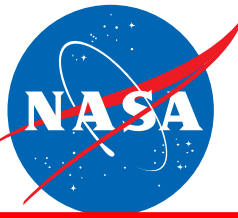
- **Hardness Assurance is the practice of designing for radiation effects**
- **What it takes to overcome the radiation challenges**
- **Competing failure modes**



Focus For Risk Acceptance



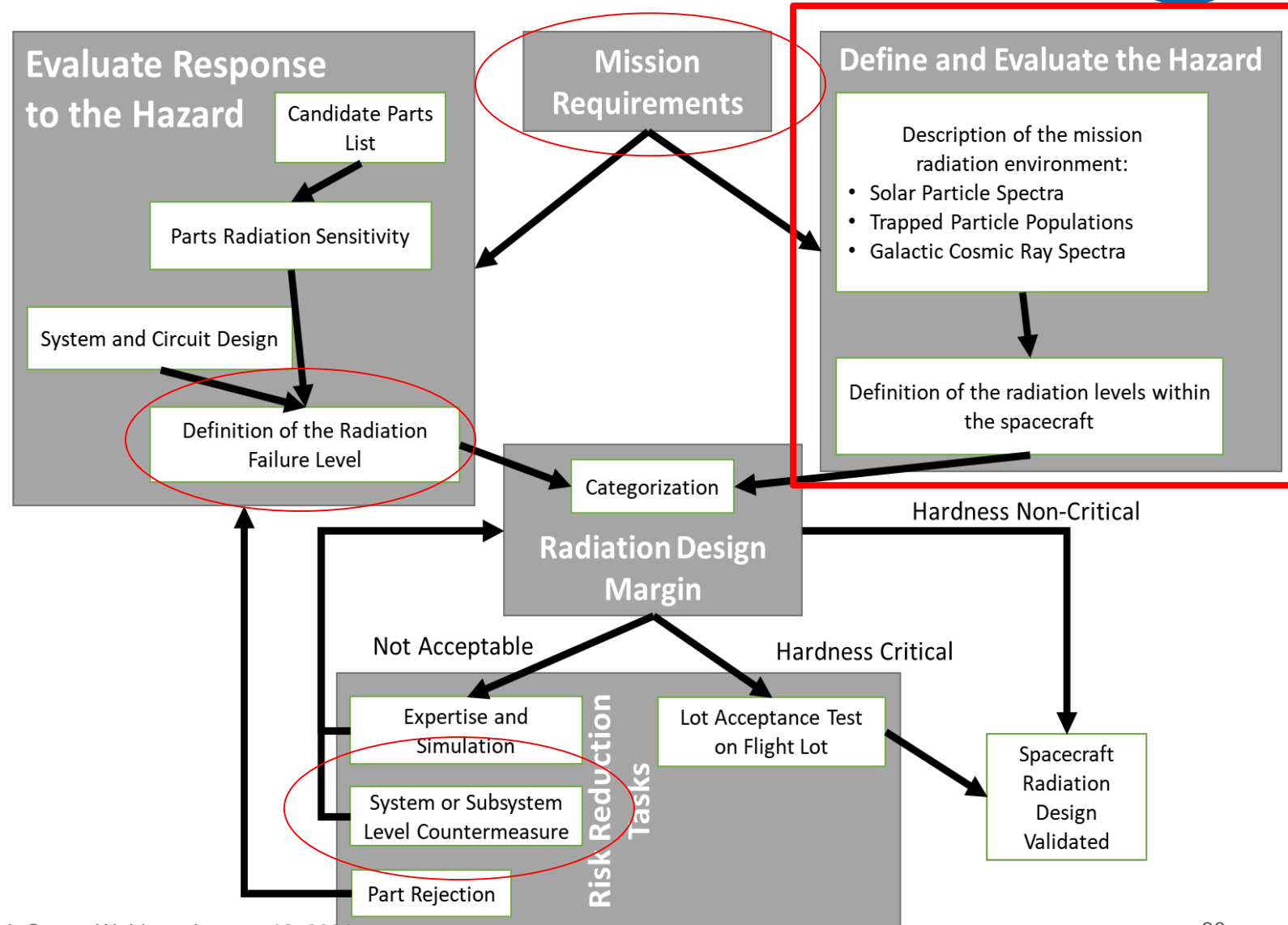
- **Failure Awareness**
 - Know your hazard from the natural environment
 - Know your devices potential failure mechanisms or response (data)
- **Countermeasures and Mitigation**
 - Where are they necessary?
 - At what level (part, card, box, mission)
- **Smart Requirements – and Eventually Smart Trades**



RHA Flow Doesn't Change With Accepted Risk

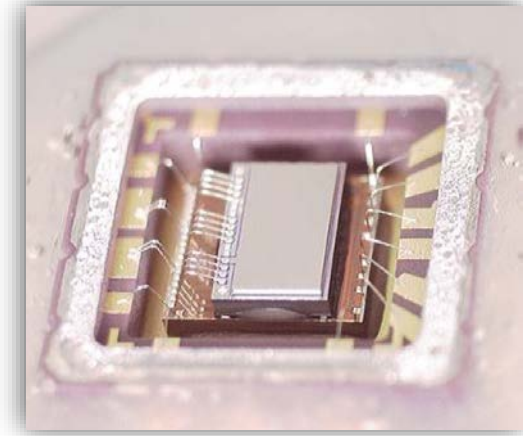
- **Hardness Assurance is the practice of designing for radiation effects**
- **What it takes to overcome the radiation challenges**
- **Competing failure modes**
- **Focus for impact on risk acceptance:**

- Failure Awareness
- Countermeasures/Mitigation
- Mission Requirements



Risks Abound, What is Critical?

- **Parts**
 - Parametric degradation and leakage currents allowable in application?
 - Downstream/peripheral circuits considered?
 - Reset/refresh capability?
 - Mitigation within too complex?
 - Predicted radiation response unknown– loss of part functionality critical?
- **Subsystem**
 - Functionally required to mission that the subsystem work?
 - Interfaces allow you to get to a known state if all goes wrong?
- **System**
 - Increased power dissipation a mission ender?
 - Availability outweighed by error circumvention?
 - Data retention through reboots? What if there is science data loss?
 - Communications interruptions overwhelm?
 - Navigation or Attitude determination unable to deal with faults?



VS.

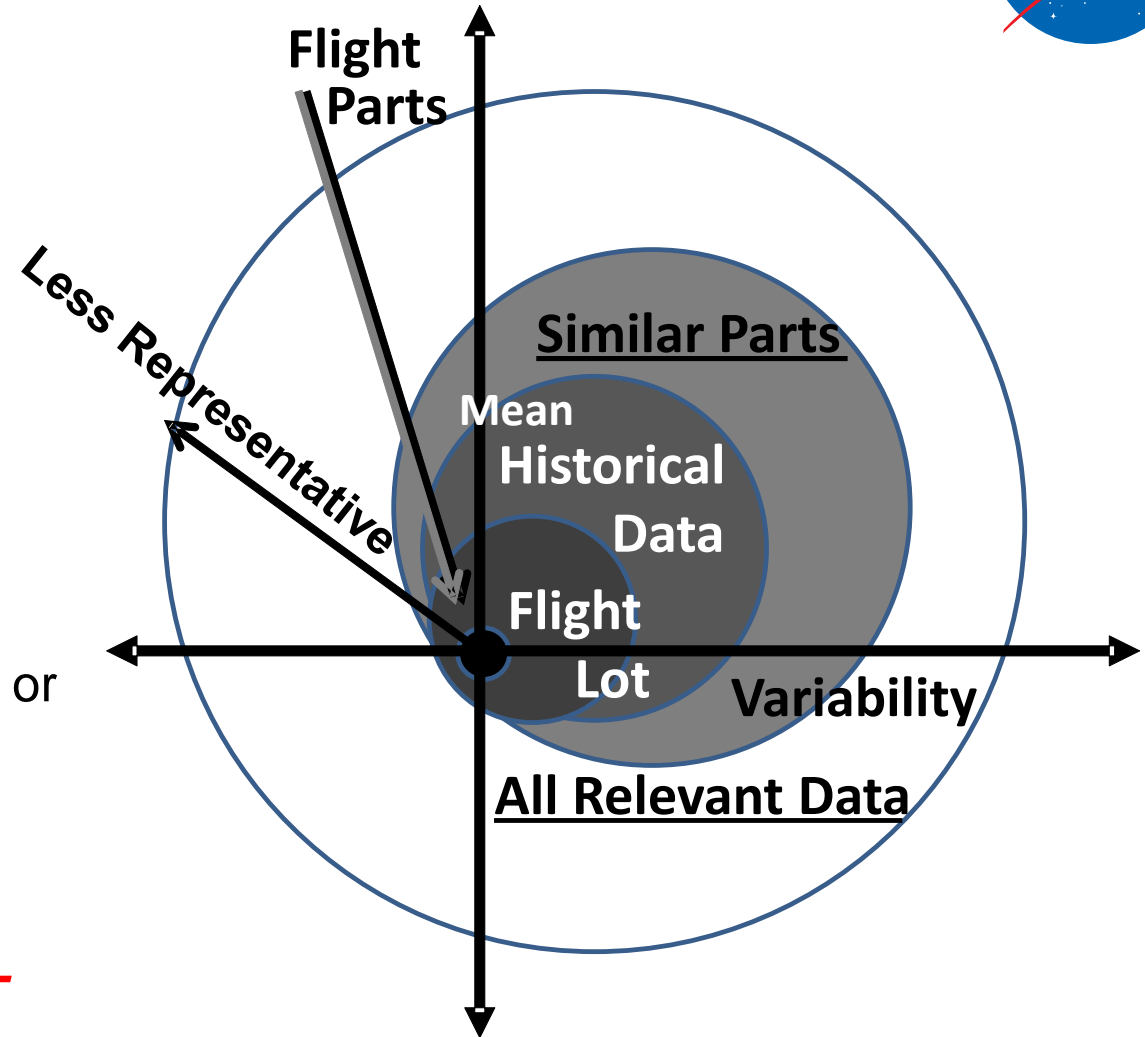


Risk Acceptance – Data Available?

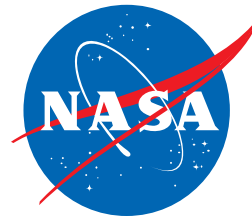


- **Part Classifications Growing**
 - Mil/Aero vs. Industrial vs. Medical
 - Automotive vs. Commercial vs. Modified HiRel
- **Substitute COTS in this diagram**
 - Now you have another degree of separation
 - Failure modes not fully understood
 - Unlikely to have historical data
 - Similarity data no applicable due to fab, process, or design rules
 - Cost of testing usually too high

Without traceability you may be depending on non-representative data.



Ray Ladbury, NSREC2017 SC,
<https://ntrs.nasa.gov/archive/nasa/casi.ntrs.nasa.gov/20170006865.pdf>



Test Costs Grow With Complexity

Pulled from the NAS Study: [Testing at the Speed of Light](#)

The State of U.S. Electronic Parts Space Radiation Testing Infrastructure

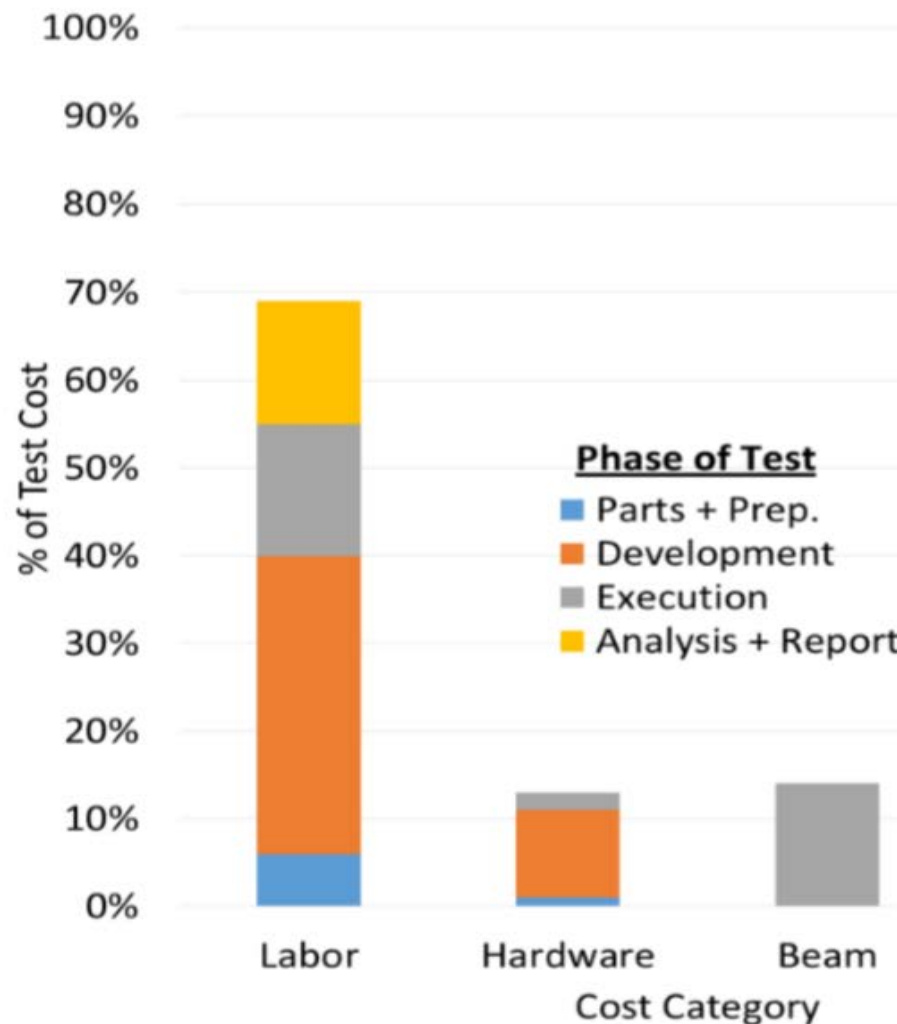


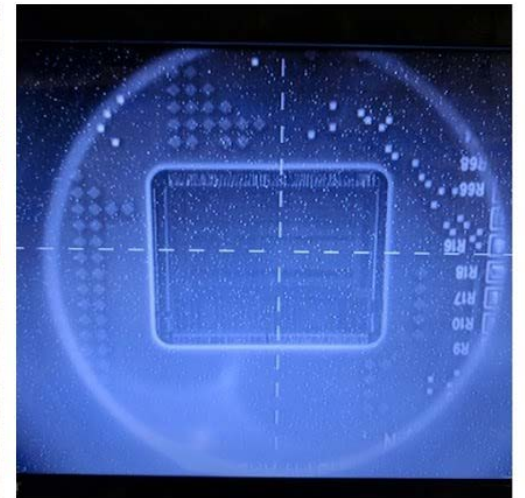
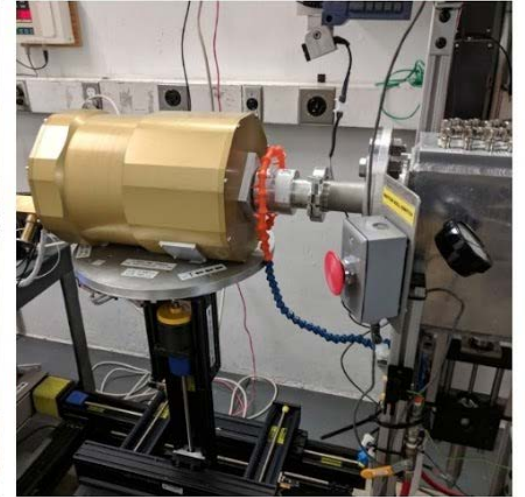
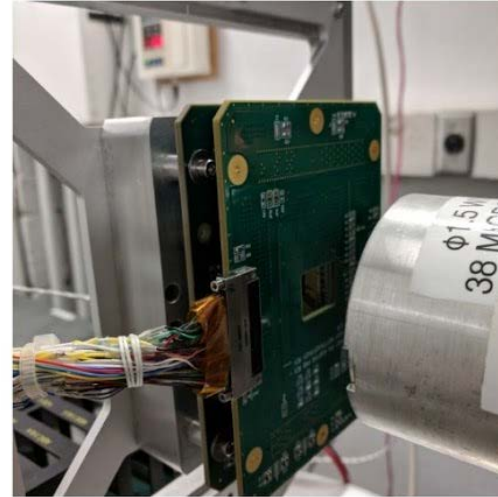
TABLE 3.2.1 Approximate Single-Event Effects Test Cost for Various Part Complexities and Packages (in thousands of dollars)

| Part Complexity/Package Difficulty | Easy | Moderate | Difficult |
|---|--------|----------|-----------|
| Simple (Op. Amp, Comparator, etc.) | 25–35 | 35–45 | >50 |
| Moderately Simple (ADC, DAC, SRAM, etc.) | 40–75 | 50–85 | >100 |
| Difficult (Flash, DRAM, Simple Processor, etc.) | 85–150 | 100–200 | >250 |
| Very Difficult (FPGA, Complex Processor, other highly complex and highly integrated components) | >500 | >550 | >600 |

NOTE: ADC, analog-to-digital converter; DAC, digital-to-analog converter; DRAM, dynamic random-access memory; FPGA, field-programmable gate array; SRAM, static random-access memory.

When Do You Test? When Do You Model?

- **Divine your risk threshold**
 - There's a doc coming for that...
radhome.gsfc.nasa.gov/nepp.nasa.gov
- **Unknown failure modes that would not be acceptable to the mission**
 - Known unknowns can be carried as a risk if you already know that the outcome is mitigated at the board or box level
 - New technologies should be identified early on
- **Fault propagation may be the problem you wish to mitigate**
 - This can include cumulative effects!
 - Fault injection may not be able to cover the state space
- **Destructive single event effects are an obvious target**
- **Can you tolerate a part replacement in your design cycle?**
 - Lead times, board re-spins, etc.



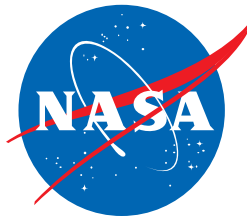


Radiation Hazard Contributors for Dose and SEE

Environment

| | | LEO Equatorial | LEO Polar (Sun Sync) | GEO / Interplanetary |
|------------------|-----------|---|--|---|
| Mission Lifetime | > 3 Years | Moderate Dose / Attenuated GCR, Trapped Proton, SAA, Some Solar Proton dependence for variation | High Dose / Higher GCR, High Energy Trapped Protons in SAA and Poles, Some Solar Proton dependence for variation | High Dose / High GCR, High Solar Proton Variability |
| | 1-3 Years | Manageable Dose / Attenuated GCR, Trapped Proton, SAA, Some Solar Proton dependence for variation | Moderate Dose / Higher GCR, High Energy Trapped Protons in SAA and Poles, Some Solar Proton dependence for variation | High Dose / High GCR, High Solar Proton Variability |
| | < 1 Year | Manageable Dose / Attenuated GCR, Trapped Proton, SAA, Some Solar Proton dependence for variation | Moderate Dose / Higher GCR, High Energy Trapped Protons in SAA and Poles, Some Solar Proton dependence for variation | Moderate Dose / High GCR, High Solar Proton Variability |

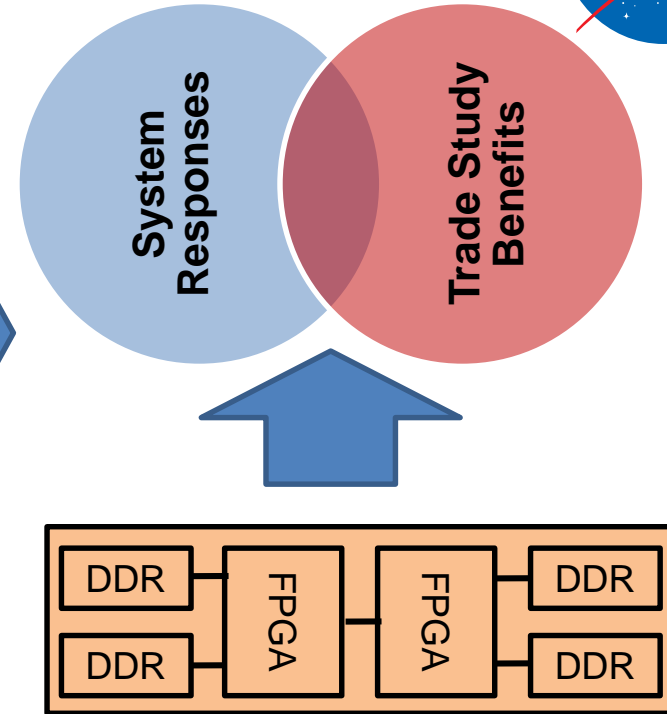
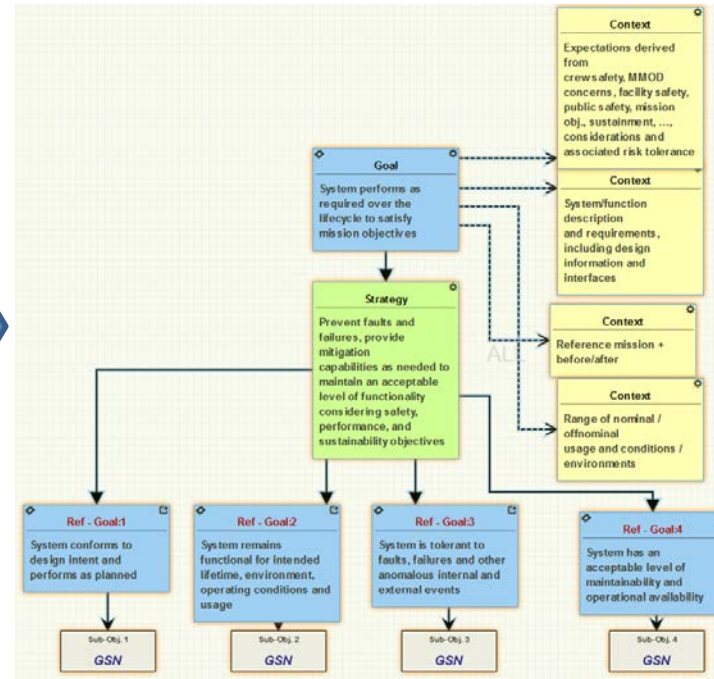
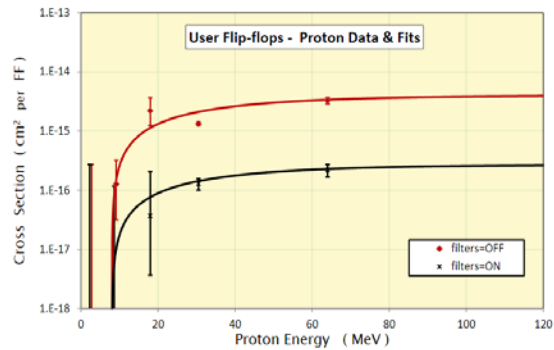
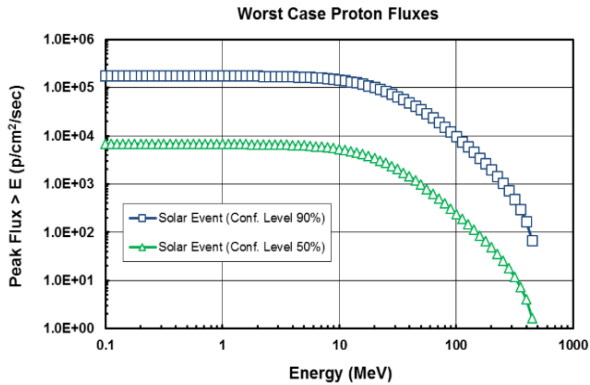
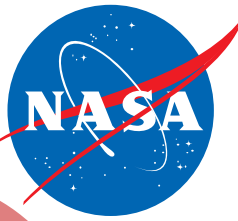
Notional Radiation Data Collection Guidelines



Environment

| | | LEO Equatorial | LEO Polar (Sun Sync) | GEO / Interplanetary |
|--|-------------|---|--|---|
| Mission Lifetime (With Assumed Risk Acceptance) | > 3 Years | Data on all SEE for critical parts, and have data on dose failure distribution on similar parts | Consider mission consequences of all SEE (Data for critical parts), have Dose failure distribution on lot | Have Data on all SEE, Have Data Dose failure distribution on lot |
| | 1 - 3 Years | Have Data on DSEE for critical parts | Consider mission consequences of all SEE (Data for critical parts), have data Dose failure distribution on similar parts | Have Data on all SEE for critical parts, Have Data on Dose failure distribution on similar parts |
| | < 1 Year | Look for data on DSEE for critical parts | Consider mission consequences of all SEE, and look for data on dose failure distribution on similar parts | Consider mission consequences of all SEE, and have data on dose failure distribution on similar parts |

Model Based Mission Assurance (MBMA) as a Tool



Environment, Device, & Design

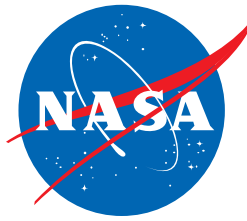
- **Models and Test Data** are brought together to get rates of upset / failure distributions
- **Resources and Utilization** are the scaling factors with criticality

Goal Structuring Notation (GSN)

- Concept of operations
- **Requirements and Availability** are fed down correctly to subsystem
- Evidence is presented
- Assumptions are tracked

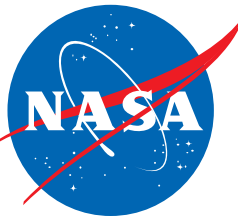
Systems Modeling Language

- Description of System Connections and Dependencies
- Receives GSN readily
- **Fault propagation** can be identified



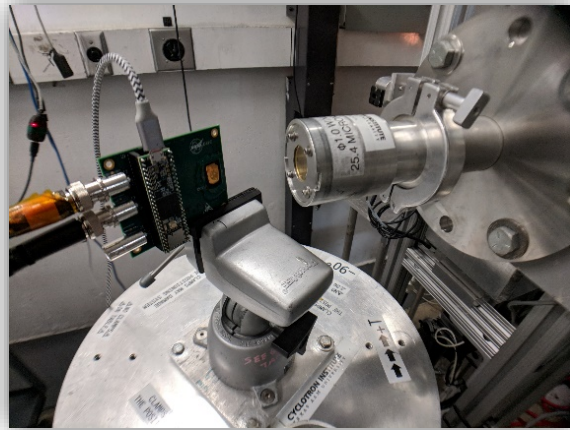
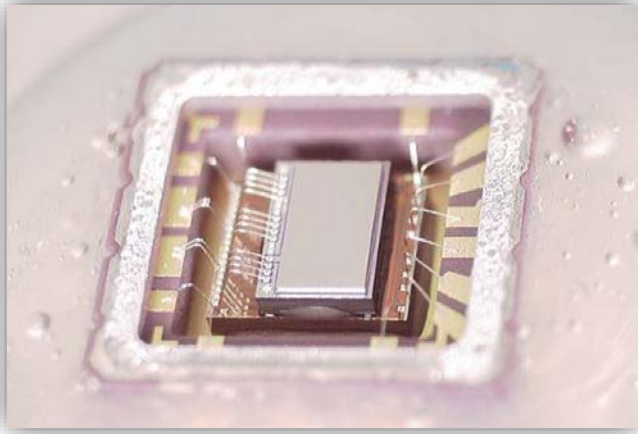
- Assign a **lead radiation engineer** to each spaceflight project
 - Treat radiation like other engineering disciplines
 - Parts, thermal,...
 - Provides a single point of contact for all radiation issues
 - Environment, parts evaluation, testing, cost/budget...
- Each program follows a **systematic approach to RHA**
 - Develop a comprehensive RHA plan
 - RHA active early in program reduces cost in the long run
 - Issues discovered late in programs can be expensive and stressful
 - What is the cost of reworking a flight board if a device has RHA issues?

PG exists for customer interface: 561-PG-8700.2.2C



Key Takeaways

- Systematic Approach is a MUST
- Early Integration with spacecraft/instrument teams
- Report to Systems Engineer or Assurance
 - Document all studies, reports, reviews
- Coordinate with Parts Engineer
- Don't be afraid to ask if you don't know
 - Don't go forward without expertise
 - Don't throw it over the fence completely
- *All work must be funded*
- Hopefully track successful performance in-flight



michael.j.campola@nasa.gov

THANK YOU